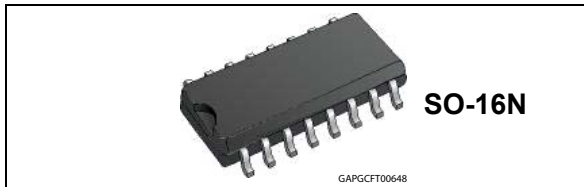


## Automotive fully integrated H-bridge motor driver

Datasheet - production data



### Features

Type	$R_{DS(on)}$	$I_{out}$	$V_{CCmax}$
VNH7070AS	70 m $\Omega$ typ (per leg)	15 A	41 V

- Automotive qualified
- Output current: 15 A
- 3 V CMOS-compatible inputs
- Undervoltage shutdown
- Overvoltage clamp
- Thermal shutdown
- Cross-conduction protection
- Current and power limitation
- Very low standby power consumption
- Protection against loss of ground and loss of  $V_{CC}$
- PWM operation up to 20 kHz
- CS diagnostic functions
  - Analog motor current feedback
  - Output short to ground detection
  - Thermal shutdown indication
  - OFF-state open-load detection
  - Output short to  $V_{CC}$  detection
- Output protected against short to ground and short to  $V_{CC}$
- Standby Mode
- Half Bridge Operation
- Package: ECOPACK<sup>®</sup>

### Description

The device is a full bridge motor driver intended for a wide range of automotive applications. The device incorporates a dual monolithic high-side driver and two low-side switches.

Both switches are designed using STMicroelectronics' well known and proven proprietary VIPower<sup>®</sup> M0-7 technology that allows to efficiently integrate on the same die a true Power MOSFET with an intelligent signal/protection circuitry. The three dies are assembled in SO-16N package on electrically isolated lead-frames.

Moreover, its fully symmetrical mechanical design allows superior manufacturability at board level. The input signals  $IN_A$  and  $IN_B$  can directly interface the microcontroller to select the motor direction and the brake condition. A SEL0 pin is available to address the information available on the CS to the microcontroller. The CS pin allows to monitor the motor current by delivering a current proportional to the motor current value. The PWM, up to 20 kHz, allows to control the speed of the motor in all possible conditions. In all cases, a low level state on the PWM pin turns off both the  $LS_A$  and  $LS_B$  switches.

**Table 1. Device summary**

Package	Order codes	
	Tube	Tape and reel
SO-16N	—	VNH7070ASTR

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# 1 Block diagram and pin description

Figure 1. Block diagram

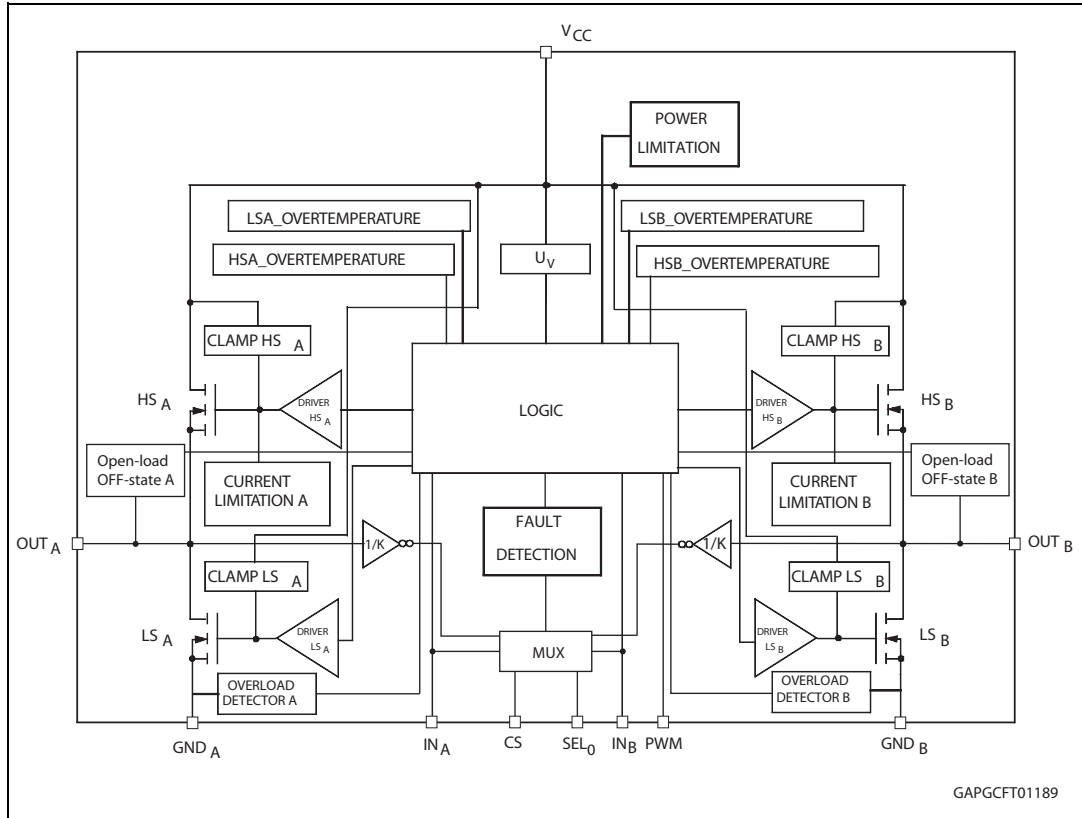


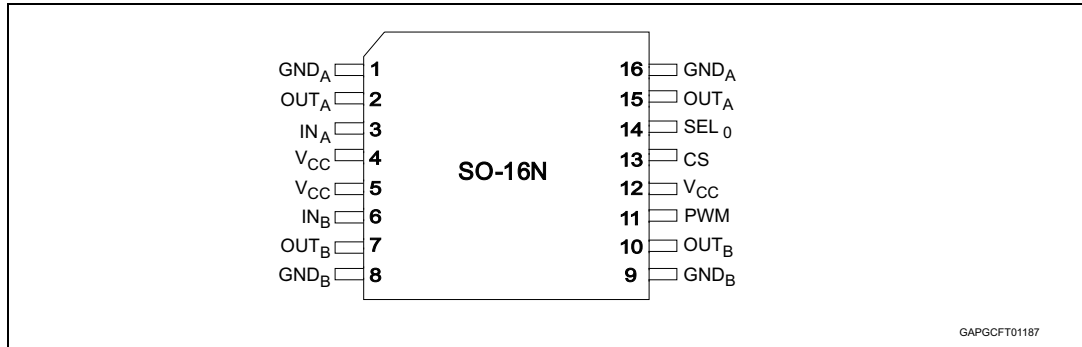
Table 2. Block description

Name	Description
Logic control	Allows the turn-on and the turn-off of the high-side and the low-side switches according to the truth table.
Undervoltage	Shuts down the device for battery voltage lower than 4 V.
High-side and low-side clamp voltage	Protect the high-side and the low-side switches from the high voltage on the battery line.
High-side and low-side driver	Drive the gate of the concerned switch to allow a proper $R_{on}$ for the leg of the bridge.
Current limitation	Limits the motor current in case of short circuit.
High-side and low-side overtemperature protection	In case of short-circuit with the increase of the junction temperature, it shuts down the concerned driver to prevent degradation and to protect the die.
Low-side overload detector	Detects when low side current exceeds shutdown current and latches off the concerned Low side.

**Table 2. Block description (continued)**

Name	Description
Fault detection	Signalizes the abnormal behavior of the switch through CS pin.
Power limitation	Limits the power dissipation of the high-side driver inside safe range in case of short to ground condition.

**Figure 2. Configuration diagram (top view)**

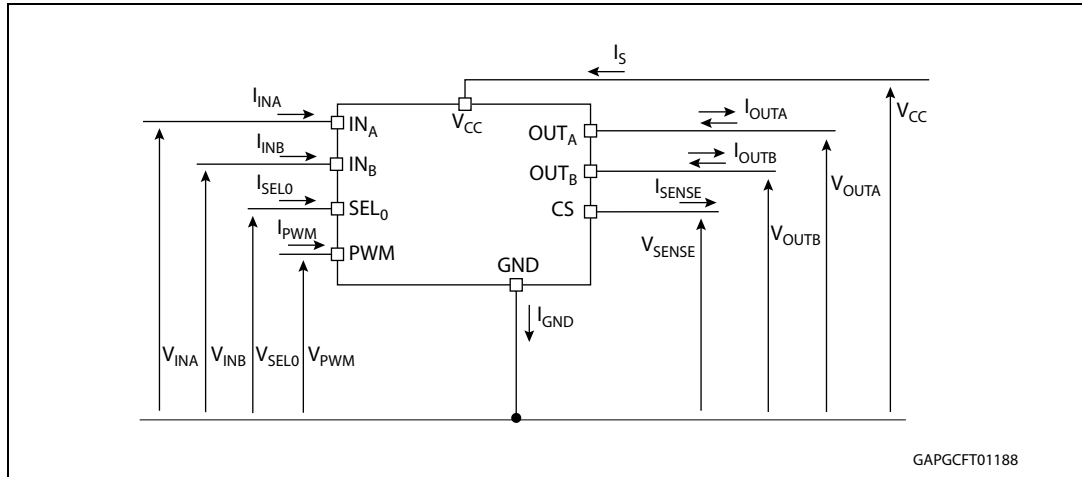


**Table 3. Pin definitions and functions**

Pin N°	Symbol	Function
1, 16	GND <sub>A</sub>	Source of low-side switch A
2, 15	OUT <sub>A</sub>	Source of high-side switch A / drain of low-side switch A
3	IN <sub>A</sub>	Clockwise input
4, 5, 12	V <sub>CC</sub>	Power supply voltage
6	IN <sub>B</sub>	Counter clockwise input
7, 10	OUT <sub>B</sub>	Source of high-side switch B / drain of low-side switch B
8, 9	GND <sub>B</sub>	Source of low-side switch B
11	PWM	Voltage controlled input pin with hysteresis, CMOS compatible. Gates of low-side FETS get modulated by the PWM signal during their on phase allowing speed control of the motor
13	CS	Multiplexed analog sense output pin; it delivers a current proportional to the motor current according to the leg selection.
14	SEL <sub>0</sub>	Active high compatible with 3 V and 5 V CMOS outputs pin; in combination with IN <sub>A</sub> , IN <sub>B</sub> , it addresses the CurrentSense information delivered to the micro according to the operative truth table.

## 2 Electrical specifications

Figure 3. Current and voltage conventions



### 2.1 Absolute maximum ratings

Stressing the device above the rating listed in [Table 4: Absolute maximum ratings](#) may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Table 4. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{CC}$	Supply voltage	38	V
$-V_{CC}$	Reverse DC Supply Voltage	0.3	V
$I_{max}$	Maximum output current (continuous)	Internally limited	A
$I_R$	Reverse output current (continuous)	-15	A
$V_{CCPK}$	Maximum transient supply voltage (ISO 16750-2:2010 Test B clamped to 40 V; $R_L = 4 \Omega$ )	40	V
$V_{CCJS}$	Maximum jump start voltage for single pulse short circuit protection	28	V
$I_{IN}$	Input current ( $IN_A$ and $IN_B$ pins)	-1 to 10	mA
$I_{SELO}$	$SEL_0$ DC input current	-1 to 10	mA
$I_{PWM}$	PWM input current	-1 to 10	mA
$I_{SENSE}$	CS pin DC output current ( $V_{GND} = V_{CC}$ and $V_{SENSE} < 0 V$ )	10	mA
	CS pin DC output current in reverse ( $V_{CC} < 0 V$ )	-20	

**Table 4. Absolute maximum ratings (continued)**

Symbol	Parameter	Value	Unit
V <sub>ESD</sub>	Electrostatic discharge (Human body model: R = 1.5 kΩ; C = 100 pF) – IN <sub>A</sub> , IN <sub>B</sub> , PWM	2	kV
	– SEL <sub>0</sub>	2	
	– CS	2	
	– V <sub>CC</sub>	4	
	– Output	4	
V <sub>ESD</sub>	Charge device model (CDM-AEC-Q100-011)	750	V
T <sub>c</sub>	Junction operating temperature	-40 to 150	°C
T <sub>STG</sub>	Storage temperature	-55 to 150	°C

## 2.2 Thermal data

**Table 5. Thermal data**

Symbol	Parameter		Max. value	Unit
R <sub>thj-pin</sub>	Thermal resistance junction-pin	HSD	31	°C/W
		LSD	44	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient (JEDEC JESD 51-2) <sup>(1)</sup>		See <a href="#">Figure 24</a>	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient (JEDEC JESD 51-2) <sup>(2)</sup>	HSD	39.5	°C/W
		LSD	55	°C/W

1. Device mounted on two-layers 2s0p PCB.
2. Device mounted on four-layers 2s2p PCB.



### 2.3 Electrical characteristics

Values specified in this section are for  $V_{CC} = 7\text{ V}$  up to  $28\text{ V}$ ;  $-40\text{ }^\circ\text{C} < T_j < 150\text{ }^\circ\text{C}$ , unless otherwise specified.

**Table 6. Power section**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{CC}$	Operating supply voltage		4		28	V
$I_S$	Supply current	Off-state - standby; $I_{N_A} = I_{N_B} = 0$ ; $SEL_0 = 0$ ; PWM = 0; $T_j = 25\text{ }^\circ\text{C}$ ; $V_{CC} = 13\text{ V}$			1	$\mu\text{A}$
		Off-state - standby; $I_{N_A} = I_{N_B} = 0$ ; $SEL_0 = 0$ ; PWM = 0; $V_{CC} = 13\text{ V}$ ; $T_j = 85\text{ }^\circ\text{C}$			1	$\mu\text{A}$
		Off-state - standby; $I_{N_A} = I_{N_B} = 0$ ; $SEL_0 = 0$ ; PWM = 0; $V_{CC} = 13\text{ V}$ ; $T_j = 125\text{ }^\circ\text{C}$			3	$\mu\text{A}$
		Off-state (no standby); $I_{N_A} = I_{N_B} = 0$ ; $SEL_0 = 5\text{ V}$ ; PWM = 0		2	4	mA
		On-state: $I_{N_A}$ or $I_{N_B} = 5\text{ V}$ ; PWM = 0 V or PWM=5 V; $SEL_0 = X$		3.5	6	mA
$t_{D\_sdbly}^{(1)}$	Standby mode blanking time	$V_{CC} = 13\text{ V}$ ; $I_{N_A} = I_{N_B} = 0\text{ V}$ ; $V_{SEL0}$ from 5 V to 0 V	0.2	1	1.8	ms
$R_{ONHS}$	Static high-side resistance	$I_{OUT} = 3.5\text{ A}$ ; $T_j = 25\text{ }^\circ\text{C}$		42		m $\Omega$
		$I_{OUT} = 3.5\text{ A}$ ; $T_j = -40\text{ to }150\text{ }^\circ\text{C}$			85	m $\Omega$
$R_{ONLS}$	Static low-side resistance	$I_{OUT} = 3.5\text{ A}$ ; $T_j = 25\text{ }^\circ\text{C}$		30		m $\Omega$
		$I_{OUT} = 3.5\text{ A}$ ; $T_j = -40\text{ }^\circ\text{C to }150\text{ }^\circ\text{C}$			60	m $\Omega$
$V_f$	Free-wheeling diode forward voltage	$I_{OUT} = -3.5\text{ A}$ ; $T_j = 150\text{ }^\circ\text{C}$		0.7	0.9	V
$I_{L(off)}$	Off-state output current of one leg	$I_{N_A} = I_{N_B} = 0$ ; PWM = 0; $V_{CC} = 13\text{ V}$ ; $T_j = 25\text{ }^\circ\text{C}$	0		0.5	$\mu\text{A}$
		$I_{N_A} = I_{N_B} = 0$ ; PWM = 0; $V_{CC} = 13\text{ V}$ ; $T_j = 125\text{ }^\circ\text{C}$	0		3	$\mu\text{A}$
$I_{L(off\_h)}$	Off-state output current of one leg with other HSD on	$I_{N_A} = 0$ ; $I_{N_B} = 5\text{ V}$ ; PWM = 0; $V_{CC} = 13\text{ V}$	20		60	$\mu\text{A}$

1. To power on the device from the standby, it is recommended to:  
 — toggle  $I_{N_A}$  or  $I_{N_B}$  from 0 to 1 first to come out from STBY mode  
 — toggle PWM from 0 to 1 with a delay of 20  $\mu\text{s}$   
 this avoids any over-stress on the device in case of existing short-to-battery.

**Table 7. Logic inputs (IN<sub>A</sub>, IN<sub>B</sub>) (V<sub>CC</sub> = 7 V up to 28 V; -40 °C < T<sub>j</sub> < 150 °C)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V <sub>IL</sub>	Input low level voltage				0.9	V
V <sub>IH</sub>	Input high level voltage		2.1			V
V <sub>IHYST</sub>	Input hysteresis voltage		0.2			V
V <sub>ICL</sub>	Input clamp voltage	I <sub>IN</sub> = 1 mA	5.3		7.2	V
		I <sub>IN</sub> = -1 mA		-0.7		V
I <sub>INL</sub>	Input current	V <sub>IN</sub> = 0.9 V	1			µA
I <sub>INH</sub>	Input current	V <sub>IN</sub> = 2.1 V			10	µA
<b>SEL<sub>0</sub> (V<sub>CC</sub> = 7 V up to 18 V; -40°C &lt; T<sub>j</sub> &lt; 150°C)</b>						
V <sub>SELL</sub>	Input low level voltage				0.9	V
I <sub>SELL</sub>	Low level input current	V <sub>SEL</sub> = 0.9 V	1			µA
V <sub>SELH</sub>	Input high level voltage		2.1			V
I <sub>SELH</sub>	High level input current	V <sub>SEL</sub> = 2.1 V			10	µA
V <sub>SEL(hyst)</sub>	Input hysteresis voltage		0.2			V
V <sub>SELCL</sub>	Input clamp voltage	I <sub>SEL</sub> = 1 mA	5.3		7.5	V
		I <sub>SEL</sub> = -1 mA		-0.7		V
<b>PWM (V<sub>CC</sub> = 7 V up to 28 V; -40°C &lt; T<sub>j</sub> &lt; 150°C)</b>						
V <sub>PWM</sub>	Input low level voltage				0.9	V
I <sub>PWM</sub>	Low level input current	V <sub>PMW</sub> = 0.9 V	1			µA
V <sub>PWM</sub>	Input high level voltage		2.1			V
I <sub>PWMH</sub>	High level input current	V <sub>PMW</sub> = 2.1 V			10	µA
V <sub>PWM(hyst)</sub>	Input hysteresis voltage		0.2			V
V <sub>PMWCL</sub>	Input clamp voltage	I <sub>PMW</sub> = 1 mA	5.3		7.2	V
		I <sub>PMW</sub> = -1 mA		-0.7		V

**Table 8. Switching (V<sub>CC</sub> = 13 V, R<sub>LOAD</sub> = 3.7 Ω)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
f <sup>(1)</sup>	PWM frequency		0		20	kHz
t <sub>d(on)</sub>	Turn-on delay time	Input rise time < 1µs (see <a href="#">Figure 6</a> )		25		µs
t <sub>d(off)</sub>	Turn-off delay time	Input rise time < 1µs (see <a href="#">Figure 6</a> )		15		µs
t <sub>r</sub>	Rise time	See <a href="#">Figure 5</a>		0.7	1.5	µs
t <sub>f</sub>	Fall time	See <a href="#">Figure 5</a>		0.2	0.5	µs
t <sub>cross</sub>	Low-side turn-on delay time	Input rise time < 1 µs (see <a href="#">Figure 7</a> )	40	140	350	µs

1. Parameter guaranteed by design and characterization; not subjected to production test.

Table 9. Protections and diagnostics ( $V_{CC} = 7\text{ V}$  up to  $18\text{ V}$ ;  $-40\text{ }^{\circ}\text{C} < T_j < 150\text{ }^{\circ}\text{C}$ )

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{USD}$	Undervoltage shutdown				4	V
$V_{USDreset}$	Undervoltage shutdown reset				5	V
$V_{USDHyst}$	Undervoltage shutdown Hysteresis			0.4		V
$I_{LIM\_H}$	High-side current limitation		15	22	30	A
$I_{SD\_LS}$	Shutdown LS current		18	27	36	A
$t_{SD\_LS}$	Time to shutdown for the low-side	$I_{N_A} = 5\text{ V}$ ; $I_{N_B} = 0\text{ V}$ ; PWM = 5 V (see <a href="#">Figure 8</a> )		5		$\mu\text{s}$
$V_{CL\_HSD}$	High-side clamp voltage ( $V_{CC}$ to $OUT_A = 0$ or $OUT_B = 0$ )	$I_{OUT} = 100\text{ mA}$ ; $t_{clamp} = 1\text{ ms}$	38	46		V
$V_{CL\_LSD}$	Low-side clamp voltage ( $OUT_A = V_{CC}$ or $OUT_B = V_{CC}$ to GND)	$I_{OUT} = 100\text{ mA}$ ; $t_{clamp} = 1\text{ ms}$	38	46		V
$T_{TSD\_HS}$	High-side thermal shutdown temperature	$I_{N_x} = 2.1\text{ V}$	150	175	200	$^{\circ}\text{C}$
$T_{TR\_HS}$	High-side thermal reset temperature		135			$^{\circ}\text{C}$
$T_{HYST\_HS}$	High-side thermal hysteresis ( $T_{SD\_HS} - T_{R\_HS}$ )			7		$^{\circ}\text{C}$
$T_{TSD\_LS}$	Low-side thermal shutdown temperature	$I_{N_x} = 0\text{ V}$	150	175	200	$^{\circ}\text{C}$
$V_{CL}$	Total clamp voltage ( $V_{CC}$ to GND)	$I_{OUT} = 100\text{ mA}$ ; $t_{clamp} = 1\text{ ms}$	38	46	52	V
$V_{OL}$	OFF-state open-load voltage detection threshold	$I_{N_A} = I_{N_B} = 0\text{ V}$ ; PWM = 0; $V_{SELO} = 5\text{ V}$ for CHA; $V_{SELO} = 0\text{ V}$ and within $t_{d\_stby}$ for CHB	2	3	4	V
$I_{L(off2)}$	OFF-state output sink current	$I_{N_A} = I_{N_B} = 0$ ; $V_{OUT} = V_{OL}$ ; PWM = 0 V; $V_{SELO} = 5\text{ V}$ for CHA; $V_{SELO} = 0\text{ V}$ and within $t_{d\_stby}$ for CHB	-100		-15	$\mu\text{A}$
$t_{DSTKON}$	OFF-state diagnostic delay time from falling edge of INPUT (see <a href="#">Figure 4</a> )	$I_{N_A} = 5\text{ V}$ to $0\text{ V}$ ; $I_{N_B} = 0$ ; $V_{SELO} = 5\text{ V}$ ; PWM = 0; $I_{OUT} = 0\text{ A}$ ; $V_{OUTA} = 4\text{ V}$	40	140	350	$\mu\text{s}$

**Table 9. Protections and diagnostics ( $V_{CC} = 7\text{ V}$  up to  $18\text{ V}$ ;  $-40\text{ }^\circ\text{C} < T_j < 150\text{ }^\circ\text{C}$ )**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{D\_VOL}$	OFF-state diagnostic delay time from rising edge of $V_{OUT}$ (see <a href="#">Figure 11</a> )	$I_{NA} = I_{NB} = 0\text{ V}$ ; $PWM = 0$ ; $V_{OUTx} = 0\text{ V}$ to $4\text{ V}$ ; $V_{SELO} = 5\text{ V}$ for CHA; $V_{SELO} = 0\text{ V}$ and within $t_{d\_stby}$ for CHB		5	30	$\mu\text{s}$
$t_{LATCH\_RST\_HS}^{(1)}$	Input reset time for high side fault unlatch (see <a href="#">Figure 9</a> )	$V_{INx} = 5\text{ V}$ to $0\text{ V}$ ; HSDx faulting	3	10	20	$\mu\text{s}$
$t_{LATCH\_RST\_LS}^{(1)}$	Input reset time for low side fault unlatch (see <a href="#">Figure 10</a> )	$V_{INx} = 0\text{ V}$ to $5\text{ V}$ ; LSDx faulting	3	10	20	$\mu\text{s}$

1. Parameter guaranteed by design and characterization; not subjected to production test.

**Table 10. CS ( $7\text{ V} < V_{CC} < 18\text{ V}$ )**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{SENSE\_CL}$	Multisense clamp voltage	$V_{CC} = 18\text{ V}$ ; $I_{SENSE} = -5\text{ mA}$		11		
		$V_{CC} = 18\text{ V}$ ; $I_{SENSE} = 5\text{ mA}$	-13		-9	V
$K_0$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 0.05\text{ A}$ ; $V_{SENSE} = 0.5\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	665			
$K_1$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 0.2\text{ A}$ ; $V_{SENSE} = 0.5\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	1083	1900	2716	
$K_2$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 3.5\text{ A}$ ; $V_{SENSE} = 4\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	1315	1540	1779	
$K_3$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 5.5\text{ A}$ ; $V_{SENSE} = 4\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	1357	1540	1727	
$dK_0/K_0^{(1)(2)}$	Analog sense current drift	$I_{OUT} = 0.05\text{ A}$ ; $V_{SENSE} = 0.5\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	-25		25	%
$dK_1/K_1^{(1)(2)}$	Analog sense current drift	$I_{OUT} = 0.2\text{ A}$ ; $V_{SENSE} = 0.5\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	-21		21	%
$dK_2/K_2^{(1)(2)}$	Analog sense current drift	$I_{OUT} = 3.5\text{ A}$ ; $V_{SENSE} = 4\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	-5		5	%
$dK_3/K_3^{(1)(2)}$	Analog sense current drift	$I_{OUT} = 5.5\text{ A}$ ; $V_{SENSE} = 4\text{ V}$ ; $T_j = -40\text{ }^\circ\text{C}$ to $150\text{ }^\circ\text{C}$	-4		4	%
$V_{SENSESAT}$	Max analog sense output voltage	$V_{CC} = 7$ ; $R_{SENSE} = 10\text{ k}\Omega$ ; $V_{SELO} = 5\text{ V}$ ; $I_{OUTA} = 5.5\text{ A}$ ; $V_{INA} = 5\text{ V}$ ; $PWM = 0$ ; $T_j = 150\text{ }^\circ\text{C}$	5			V
$I_{SENSE\_SAT}^{(2)}$	CurrentSense saturation current	$V_{CC} = 13\text{ V}$ ; $V_{INA} = 5\text{ V}$ ; $V_{INB} = 0\text{ V}$ ; $V_{SENSE} = 4\text{ V}$ ; $V_{SELO} = 5\text{ V}$ ; $T_j = 150\text{ }^\circ\text{C}$	4.6			mA
$I_{OUT\_SAT}^{(2)}$	Output saturation current	$V_{CC} = 13\text{ V}$ ; $V_{SENSE} = 4\text{ V}$ ; $V_{INA} = 5\text{ V}$ ; $V_{INB} = 0\text{ V}$ ; $V_{SELO} = 5\text{ V}$ ; $T_j = 150\text{ }^\circ\text{C}$	8			A

Table 10. CS (7 V < V<sub>CC</sub> < 18 V) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V <sub>OUT_MSD</sub> <sup>(2)</sup>	Output Voltage for MultiSense shutdown	V <sub>INA</sub> = 5 V; V <sub>INB</sub> = 0 V; V <sub>SELO</sub> = 5 V; R <sub>SENSE</sub> = 2.7 kΩ; I <sub>OUT</sub> = 3.5 A		5		V
I <sub>SENSE0</sub>	CS leakage current	I <sub>OUT</sub> = 0 A; V <sub>SENSE</sub> = 0 V; I <sub>N<sub>x</sub></sub> = 0 V; SEL <sub>0</sub> = 0; T <sub>j</sub> = -40°C to 150°C (Standby)	0		0.5	μA
		I <sub>OUT</sub> = 0 A; V <sub>SENSE</sub> = 0 V; I <sub>N<sub>x</sub></sub> = 0 V; SEL <sub>0</sub> = 5 V; T <sub>j</sub> = -40°C to 150°C (No Standby)	0		0.5	μA
		I <sub>N<sub>x</sub></sub> = 5 V; PWM = 5 V; I <sub>OUT</sub> = 0 A; T <sub>j</sub> = -40°C to 150°C	0		5	μA
V <sub>SENSEH</sub>	CS output voltage in fault condition	V <sub>CC</sub> = 13 V; R <sub>SENSE</sub> = 1 kΩ; – E.g. Out <sub>A</sub> in open-load: V <sub>INA</sub> = 0 V; I <sub>OUTA</sub> = 0 A; V <sub>OUTA</sub> = 4 V; V <sub>SELO</sub> = 5 V	5		7	V
I <sub>SENSEH</sub>	CS output current in fault condition	V <sub>CC</sub> = 13 V; V <sub>SENSE</sub> = V <sub>SENSEH</sub>	7	20	30	mA

1. Analog sense current drift is deviation of factor K for a given device over (-40 °C to 150 °C and 9 V < V<sub>CC</sub> < 18 V) with respect to its value measured at T<sub>j</sub> = 25 °C, V<sub>CC</sub> = 13 V.
2. Parameter guaranteed by design and characterization; not subjected to production test.

Figure 4. T<sub>DSTKON</sub>

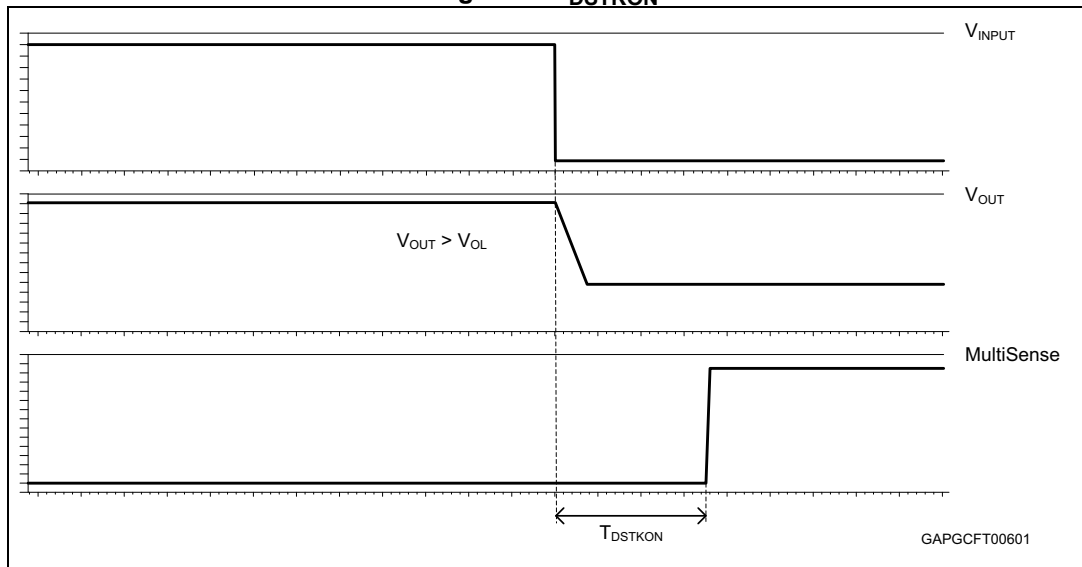


Figure 5. Definition of the low-side switching times

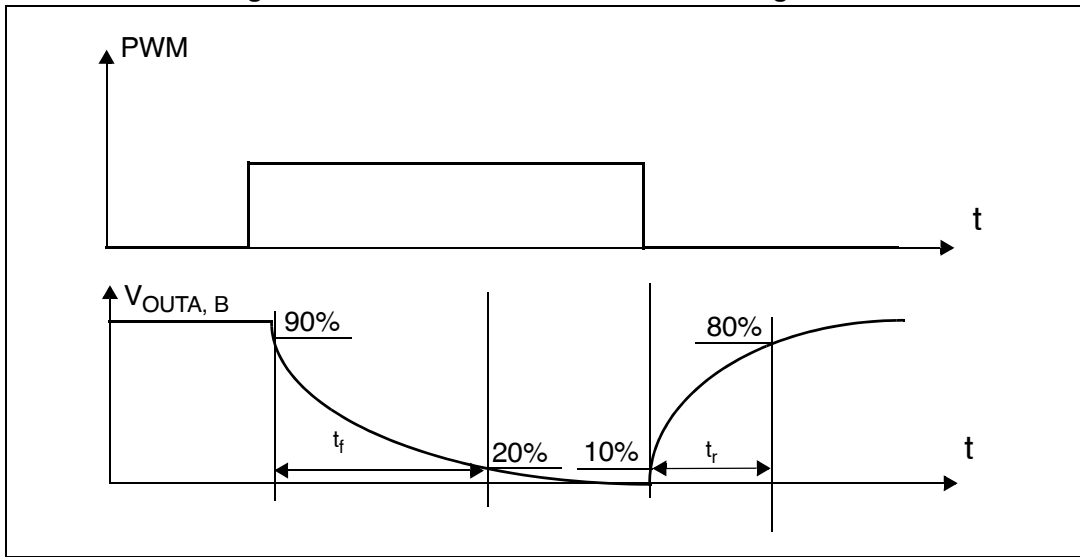


Figure 6. Definition of the high-side switching times

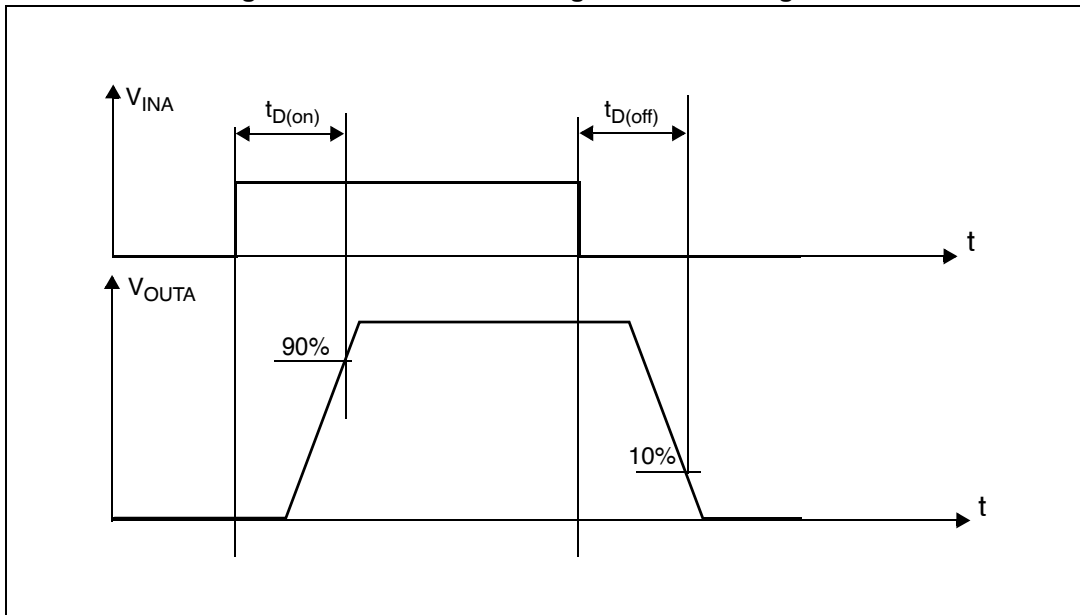


Figure 7. Low-side turn-on delay time

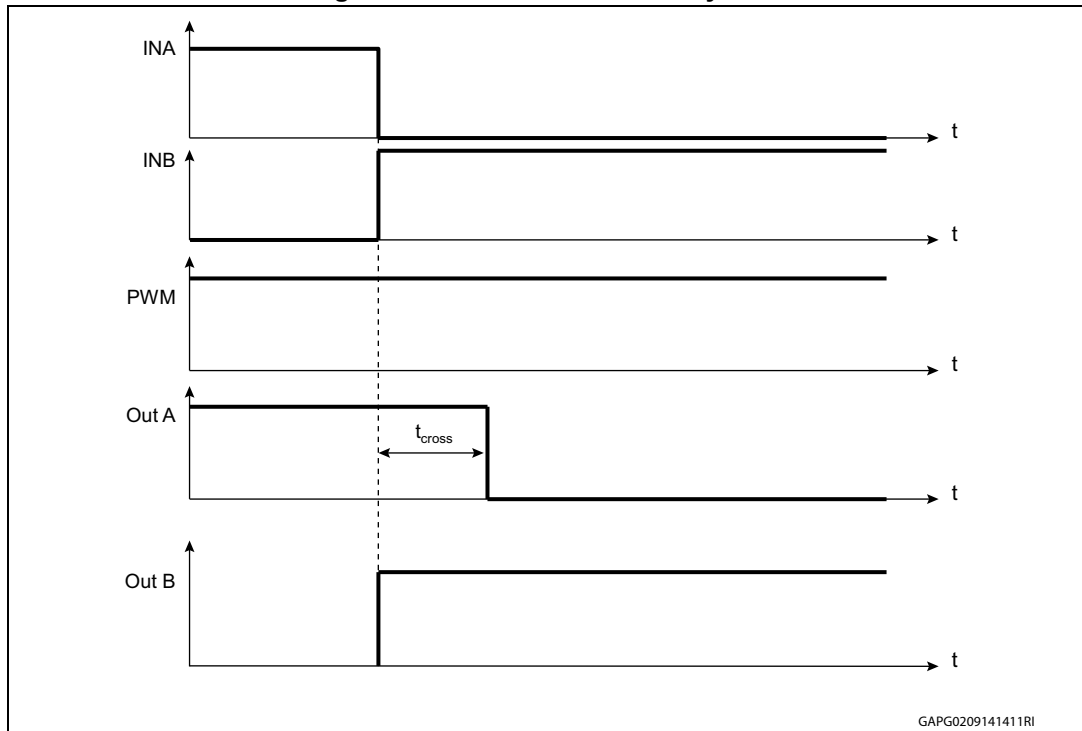


Figure 8. Time to shutdown for the low-side driver

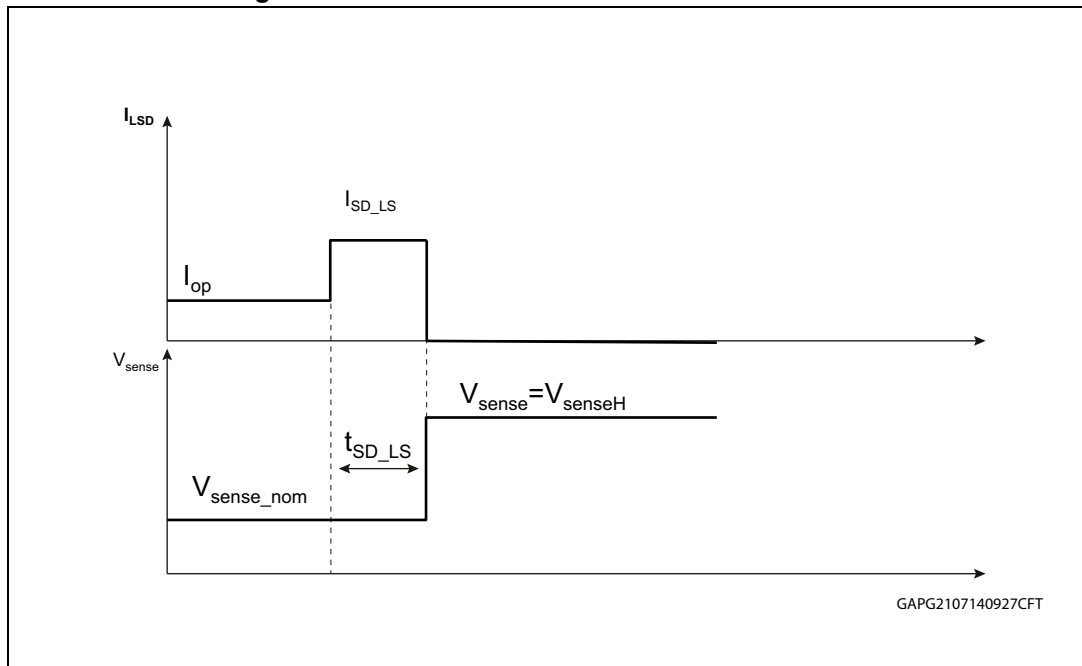


Figure 9. Input reset time for HSD - fault unlatch

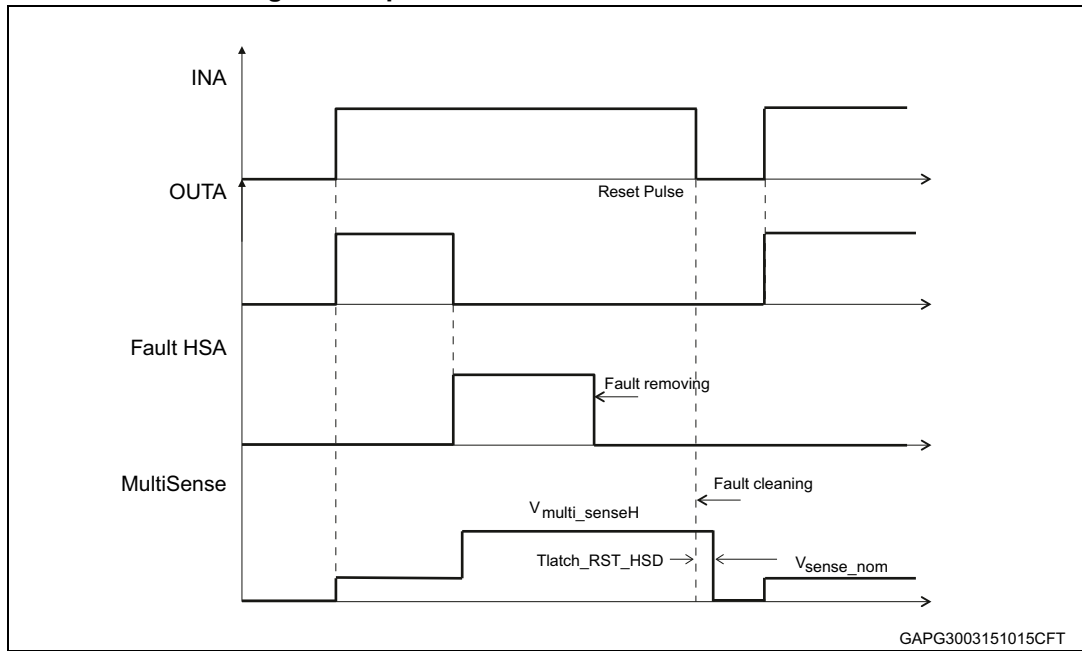


Figure 10. Input reset time for LSD - fault unlatch

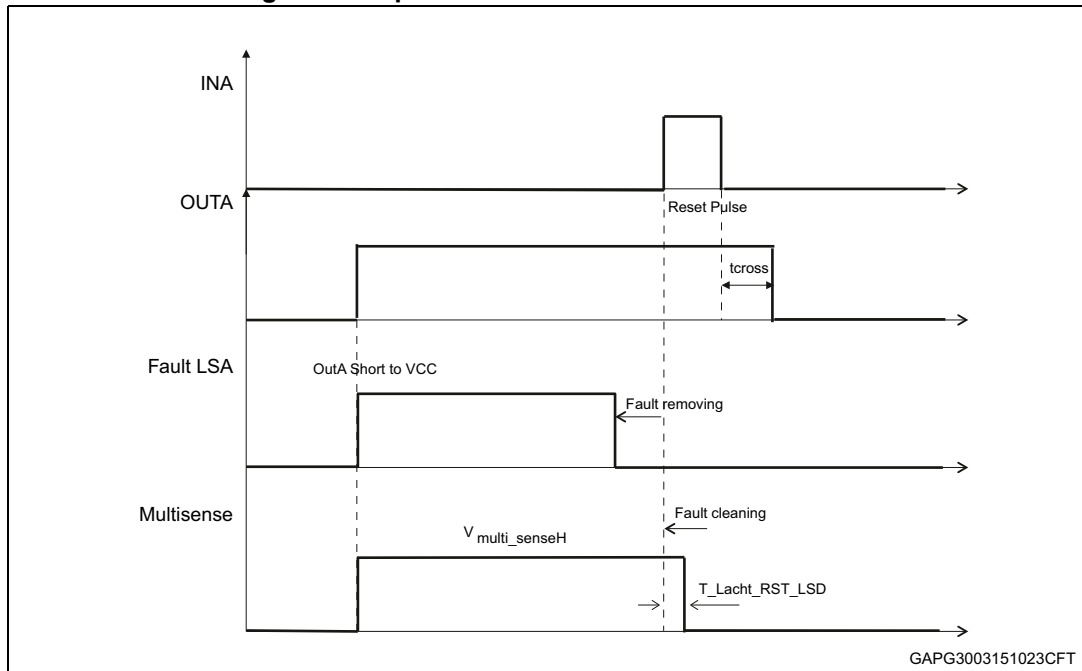
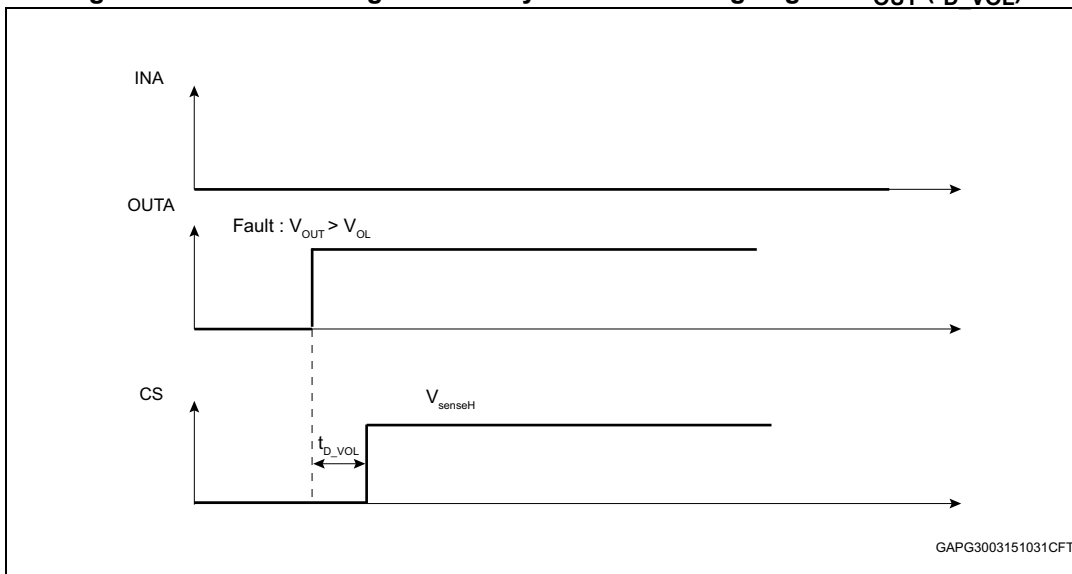




Figure 11. OFF-state diagnostic delay time from rising edge of  $V_{OUT}$  ( $t_{D\_VOL}$ )



**Table 11. Operative condition - truth table**

Pin status					HSDs and LDSs status			
IN <sub>A</sub>	IN <sub>B</sub>	SEL <sub>0</sub>	PWM	CS	HSDA	LSDA	HSDB	LSDB
1	1	1	x	Current Monitoring HSDA	On	Off	On	Off
		0		Current Monitoring HSDB				
1	0	1	1	Current Monitoring HSDA	On	Off	Off	On
			0		On	Off	Off	Off
1	0	0	1	Hi-Z	On	Off	Off	On
			0		On	Off	Off	Off
0	1	1	1	Hi-Z	Off	On	On	Off
			0		Off	Off	On	Off
0	1	0	1	Current Monitoring HSDB	Off	On	On	Off
			0		Off	Off	On	Off
0	0	1	1	Hi-Z	Off	On	Off	On
		0						
0	0	1	0	x <sup>(1)</sup>	Off	Off	Off	Off
		0 <sup>(2)</sup>						

1. Refer to [Table 13: Off-state -truth table](#)
2. For IN<sub>A</sub> = IN<sub>B</sub> = SEL<sub>0</sub> = PWM = 0, the device enters in standby after T<sub>D\_sdb</sub>y

**Table 12. On-state fault conditions- truth table**

Digital Input pins				CS	Comment
INA	INB	PWM	SELO		
0	0	1	0	VsenseH	LSB protection triggered; LSB latched off
0	0	1	1	VsenseH	LSA protection triggered; LSA latched off
0	1	X	0	VsenseH	HSB protection triggered; HSB latched off
0	1	1	1	VsenseH	LSA protection triggered; LSA latched off
1	0	1	0	VsenseH	LSB protection triggered; HSB latched off
1	0	X	1	VsenseH	HSA protection triggered; HSA latched off
1	1	X	0	Hi-Z	HSB protection triggered; HSB latched off
1	1	X	1	Hi-Z	HSA protection triggered; HSA latched off

*Note:* Other logic combinations on digital input pins not reported on the above table don't allow to detect a latched off channel.

Table 13. Off-state -truth table

IN <sub>A</sub>	IN <sub>B</sub>	SEL <sub>0</sub>	PWM	Out <sub>A</sub>	Out <sub>B</sub>	CS	Description
<b>Off-state diagnostic</b>							
0	0	1	0	$V_{outA} > V_{OL}$	x	$V_{SENSEH}$	Case 1. Out <sub>A</sub> shorted to V <sub>CC</sub> if no pull-up is applied Case 2. No open-load in full bridge configuration with an external pull-up on Out <sub>B</sub> Case 3. open-load in half bridge configuration with an external pull-up on Out <sub>A</sub> (motor connected between Out <sub>A</sub> and Ground)
				$V_{outA} < V_{OL}$	x	Hi-Z	Case 1. Open-load in full Bridge configuration with an external pull-up on Out <sub>B</sub> Case 2. No open-load in half Bridge configuration with external pull-up on Out <sub>A</sub> (motor connected between Out <sub>A</sub> and Ground)
	0 <sup>(1)(2)</sup>	x		$V_{outB} > V_{OL}$	$V_{SENSEH}$	Case 1. Out <sub>B</sub> shorted to V <sub>CC</sub> if no pull-up is applied Case 2. No open-load in full bridge configuration with external pull-up on Out <sub>A</sub> Case 3. Open-load in half bridge configuration with external pull-up on Out <sub>B</sub> (motor connected between Out <sub>B</sub> and Ground)	
		x		$V_{outB} < V_{OL}$	Hi-Z	Case1. Open-load in full Bridge configuration with an external pull-up on Out <sub>A</sub> Case 2. No open-load in half Bridge configuration with external pull-up on Out <sub>B</sub> (motor connected between Out <sub>B</sub> and Ground)	

1. The device enters standby mode after T<sub>D\_sdbdy</sub>.
2. To power on the device from the standby, it is recommended to toggle INA or INB from 0 to 1 first and then PWM from 0 to 1 to avoid any over-stress on the device in case of short-to-battery.

## 2.4 Waveforms

Figure 12. Normal operative conditions

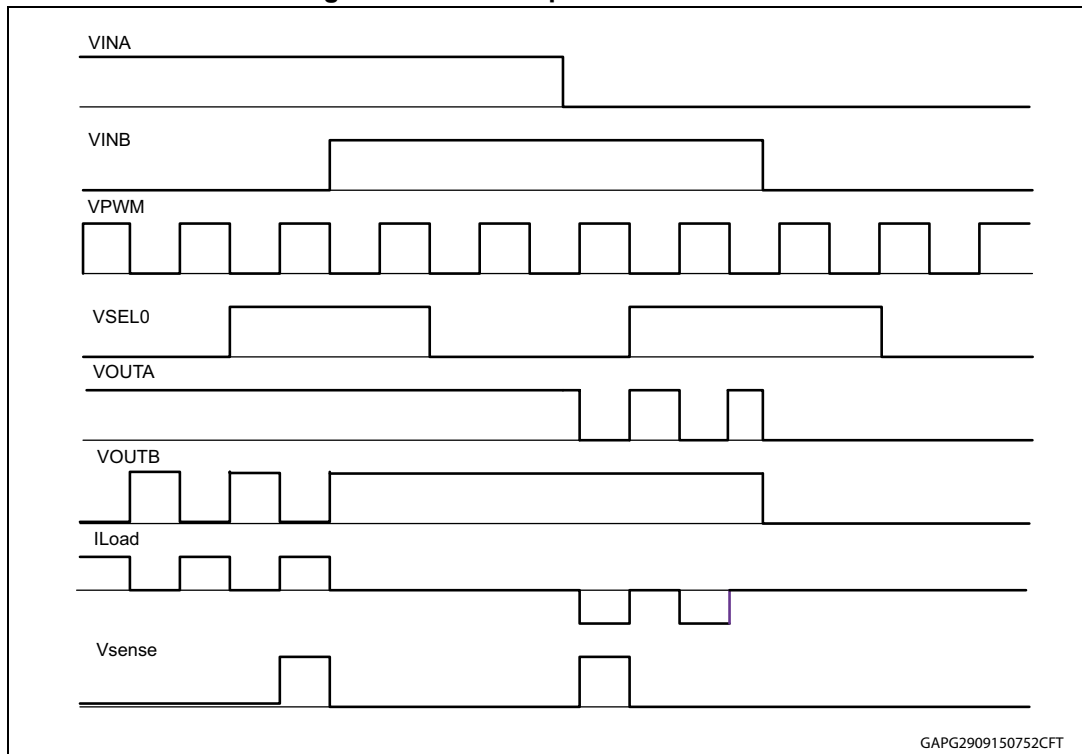


Figure 13. OUT shorted to ground and short clearing

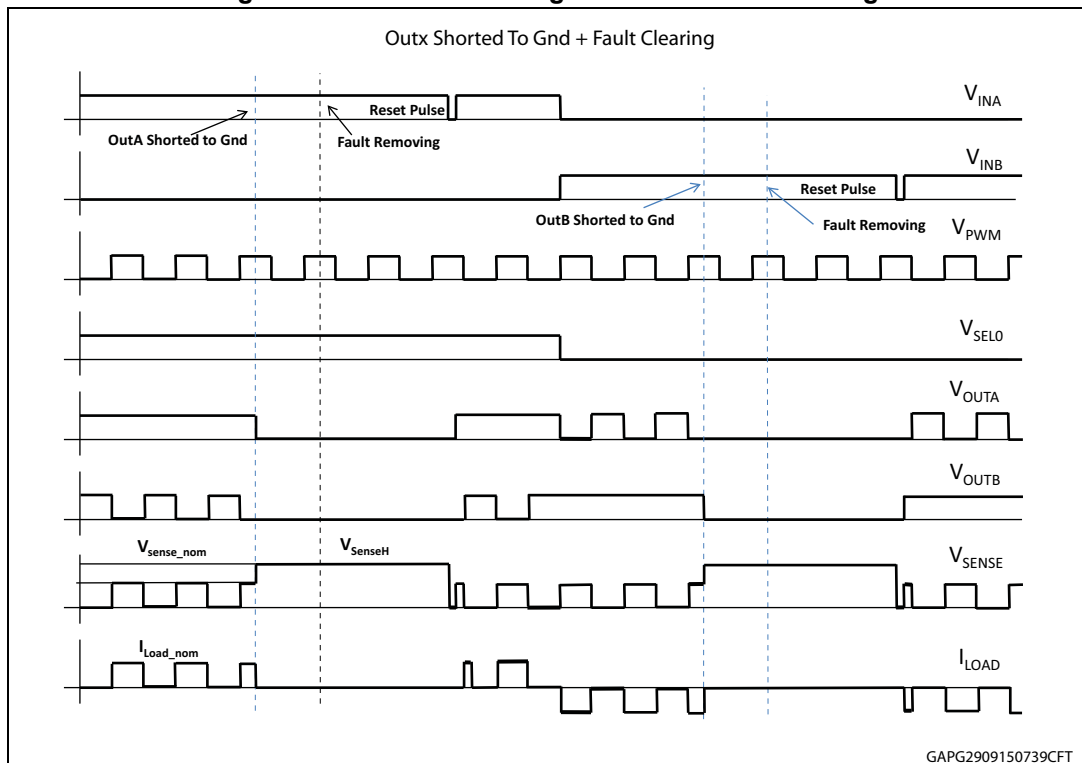
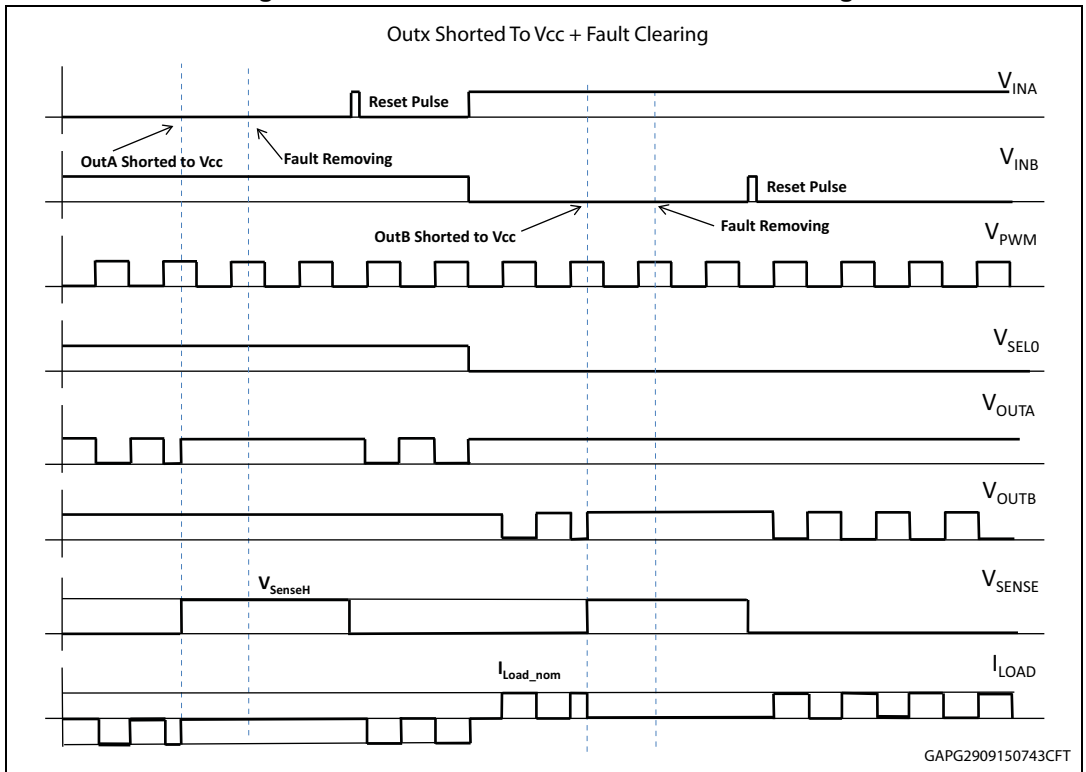


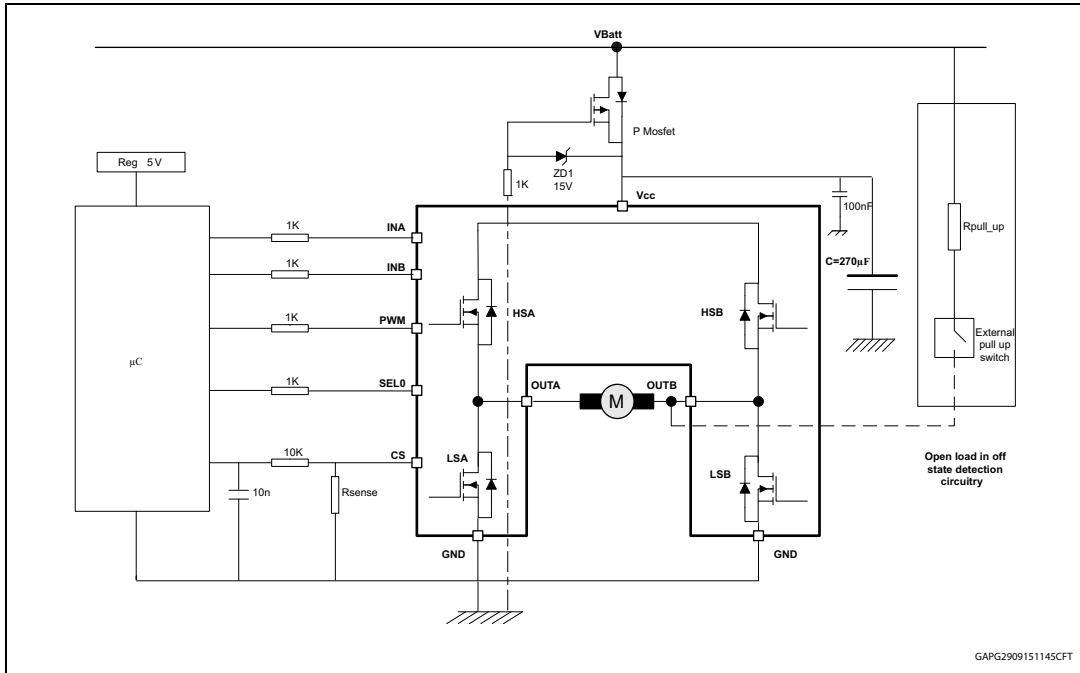
Figure 14. OUT shorted to Vcc and short clearing



### 3 Application information

Here following there is the typical application schematic suggested for a proper operation of the device in DC or PWM conditions.

**Figure 15. Application schematic with reverse battery protection connected to Vbatt**



**Figure 16. Application schematic with reverse battery protection connected to GND**

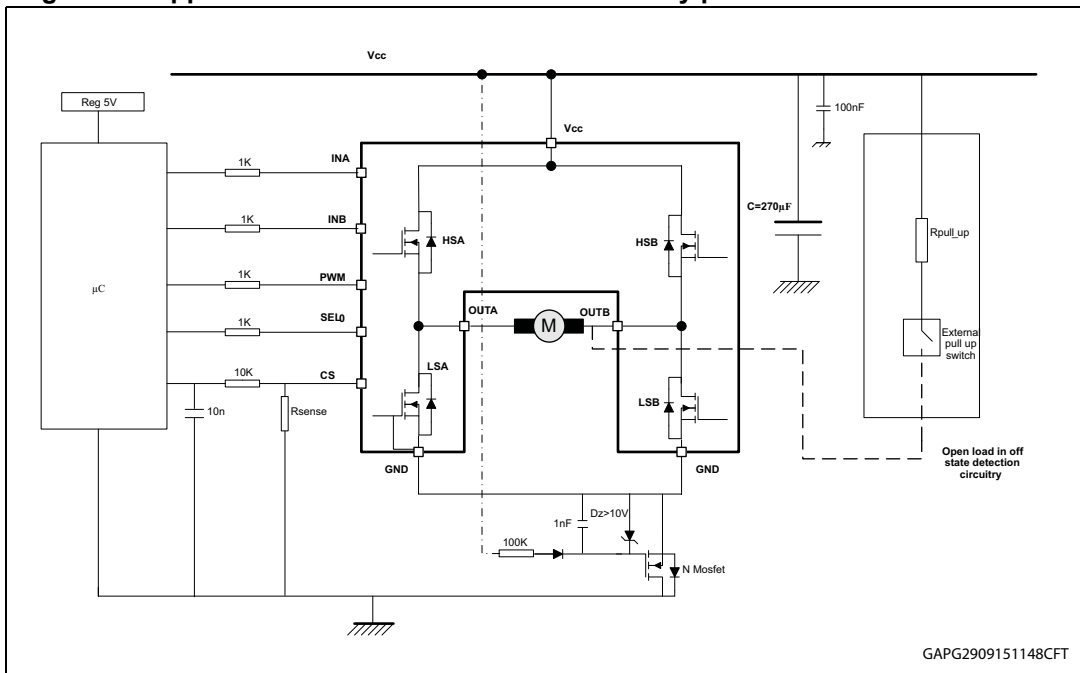
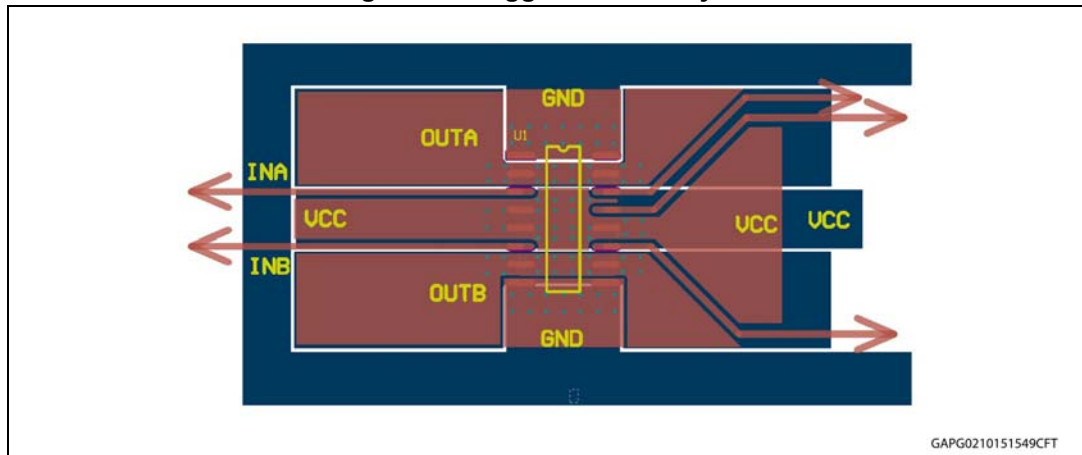


Figure 17. Suggested PCB layout



Note: *PCB layout recommendation:  
Optimized connection (short) between Drain LSD and Source HSD  
Optimized GNDa and GNDb connection (symmetric connection)*

### 3.1 Reverse battery protection

Three possible solutions can be considered:

- A Schottky diode D connected to V<sub>CC</sub> pin
- An N-channel MOSFET connected to the GND pin
- A P-channel MOSFET connected to the V<sub>CC</sub> pin

In case the reverse battery protection is not present, the device sustains no more than -15 A because of the two Body diodes of the Power MOSFETs. Additionally, in reverse battery condition the I/Os of the device is pulled down to the V<sub>CC</sub> line (approximately -1.5 V).

Series resistor must be inserted to limit the current sunk from the microcontroller I/Os. If I<sub>Rmax</sub> is the maximum target reverse current through microcontroller I/Os, series resistor is:

$$R = \frac{V_{IOs} - V_{CC}}{I_{Rmax}}$$

### 3.2 OFF-state open-load detection – External circuitry dimensioning

The detection of an open-load in off state requires an external circuitry to be connected between Output and V<sub>BATT</sub>.

For the detection it is necessary to put one network on each leg in case of Half Bridge operation or one network on one of the output in case of full bridge (see [Table 13: Off-state -truth table](#)).

The external circuitry is made up by an external pull-up resistor R<sub>pull\_up</sub> connecting the output to a positive supply voltage V<sub>PU</sub> (V<sub>Batt</sub>).

It is preferable to switch-off  $V_{PU}$  by using an external pull\_up switch to reduce the overall standby current during the module standby mode.

$R_{pull\_up}$  must be dimensioned to ensure that in normal operative conditions  $V_{OUT} > V_{OLmax}$ .

To satisfy this condition the  $R_{pull\_up}$  must be selected according to:

- if the device is used in half bridge configuration, the equation is:

$$R_{pull\_up} < \frac{V_{BATTmin} - V_{OLmax}}{I_{L(off2)min}[@VOLmax]}$$

- if the device is used in H-bridge configuration, the equation is:

$$R_{pull\_up} < \frac{V_{BATTmin} - V_{OLmax}}{2 \times I_{L(off2)min}[@VOLmax]}$$

### 3.3 Immunity against transient electrical disturbances

The immunity of the device against transient electrical emissions, conducted along the supply lines and injected into the  $V_{CC}$  pin, is tested in accordance with ISO7637-2:2011 (E) and ISO 16750-2:2010.

The related function performance status classification is shown in [Table 14](#).

Test pulses are applied directly to DUT (Device Under Test) both in ON and OFF-state and in accordance to ISO 7637-2:2011(E), chapter 4. The DUT is intended as the present device only, without components and accessed through  $V_{CC}$  and GND terminals.

Status II is defined in ISO 7637-1 Function Performance Status Classification (FPSC) as follows: "The function does not perform as designed during the test but returns automatically to normal operation after the test".

**Table 14. ISO 7637-2 - electrical transient conduction along supply line**

Test Pulse 2011(E)	Test pulse severity level with Status II functional performance status		Minimum number of pulses or test time	Burst cycle / pulse repetition time		Pulse duration and pulse generator internal impedance
	Level	$U_S^{(1)}$		min	max	
1	III	-112 V	500 pulses	0,5 s		2ms, 10 $\Omega$
2a	III	+55 V	500 pulses	0,2 s	5 s	50 $\mu$ s, 2 $\Omega$
3a	IV	-220 V	1h	90 ms	100 ms	0.1 $\mu$ s, 50 $\Omega$
3b	IV	+150 V	1h	90 ms	100 ms	0.1 $\mu$ s, 50 $\Omega$
4 <sup>(2)</sup>	IV	-7 V	1 pulse			100ms, 0.0 1 $\Omega$
<b>Load dump according to ISO 16750-2:2010</b>						
Test B <sup>(3)</sup>		40 V	5 pulse	1 min		400 ms, 2 $\Omega$

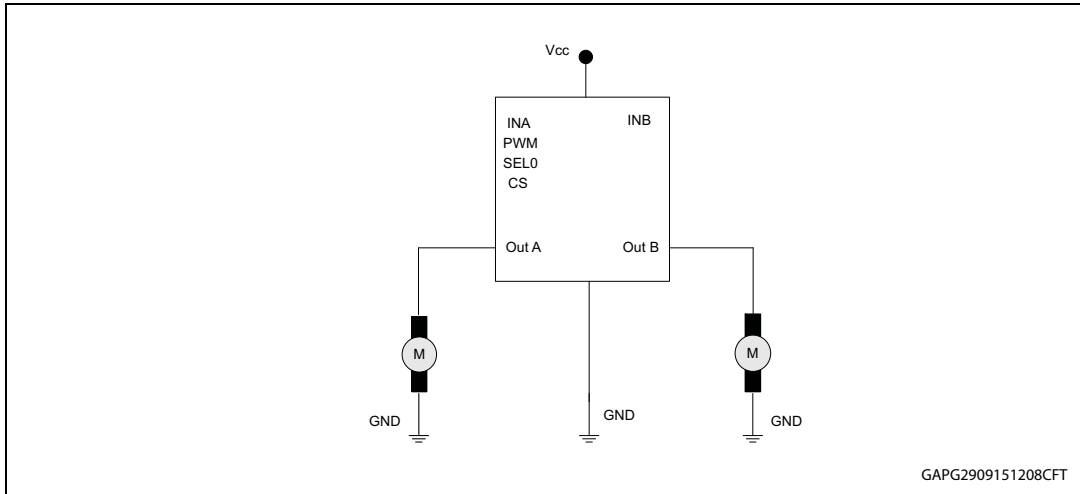
1.  $U_S$  is the peak amplitude as defined for each test pulse in ISO 7637-2:2011(E), chapter 5.6.



2. Test pulse from ISO 7637-2:2004(E).
3. With 40 V external suppressor referred to ground ( $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$ ).

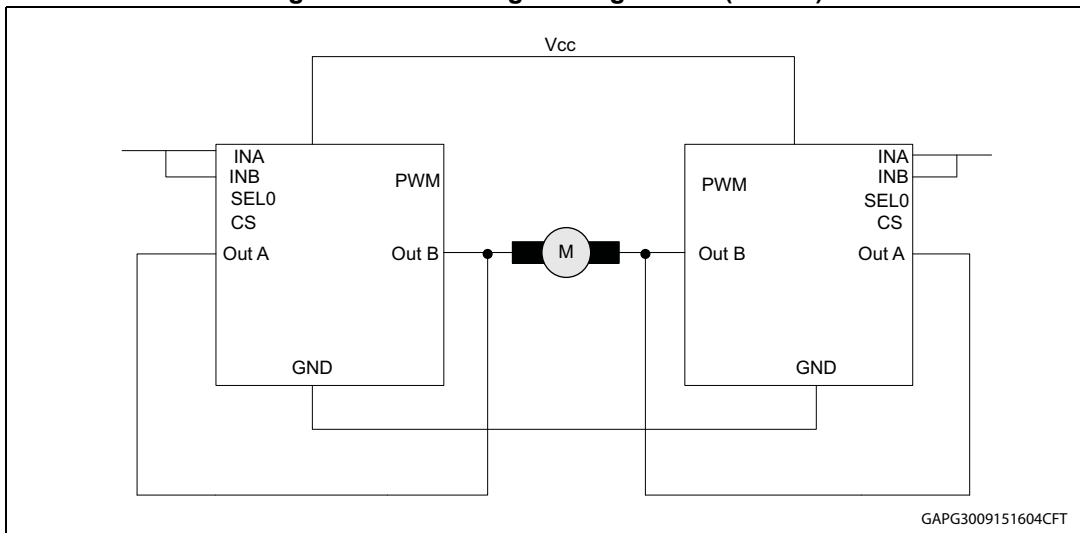
### 3.4 Device configurations

Figure 18. Half-bridge configuration (case a)



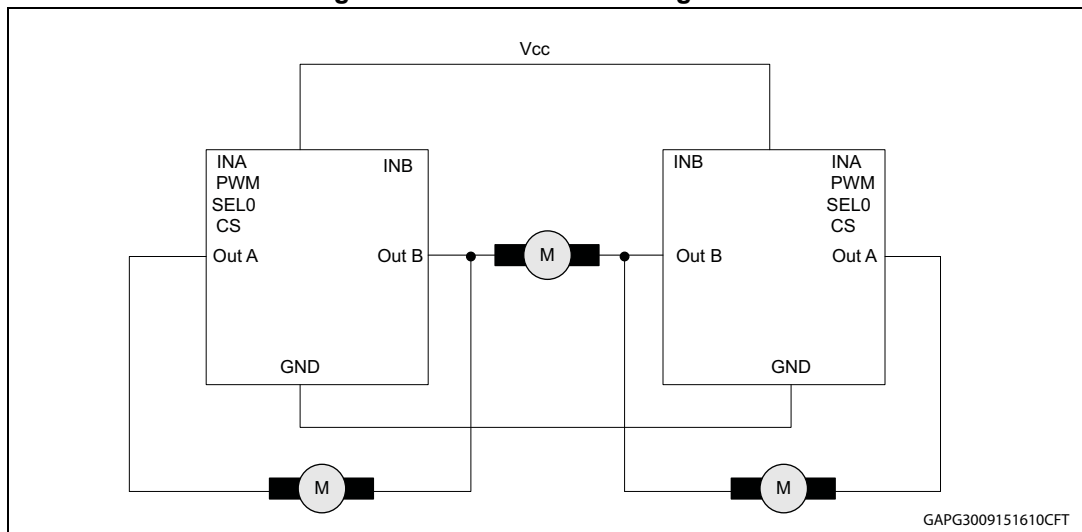
*Note:* The VNH7070AS can be used in half bridge configuration as the two legs can be independently driven. The SEL0 pin can be used to address the diagnostic on the CS according to the operative truth table.

Figure 19. Half-bridge configuration (case b)



*Note:* The VNH7070AS can be used in applications where an half-bridge with a resistance of 50 mΩ per leg is needed.

Figure 20. Multi-motors configuration



*Note:* The VNH7070AS can easily be designed in multi motor driving configuration in the applications where only one motor at a time must be activated. The SEL0 pin can be used to read the diagnostic on the CS according to the operative truth table.

## 4 Package and PCB thermal data

### 4.1 SO16-N thermal data

Figure 21. PCB layout (top and bottom): footprint, 2+2+2 cm<sup>2</sup>, 8+8+8 cm<sup>2</sup>

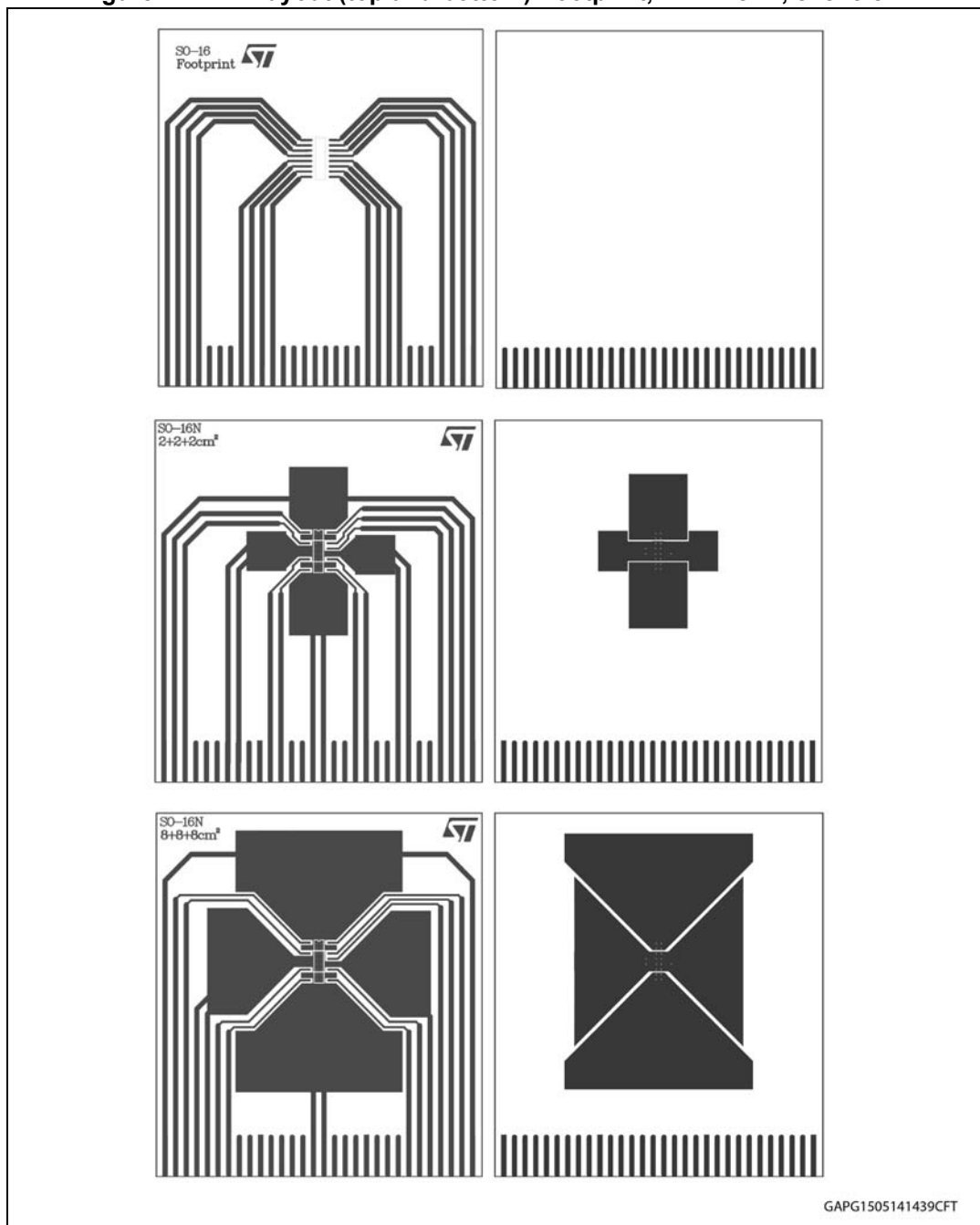
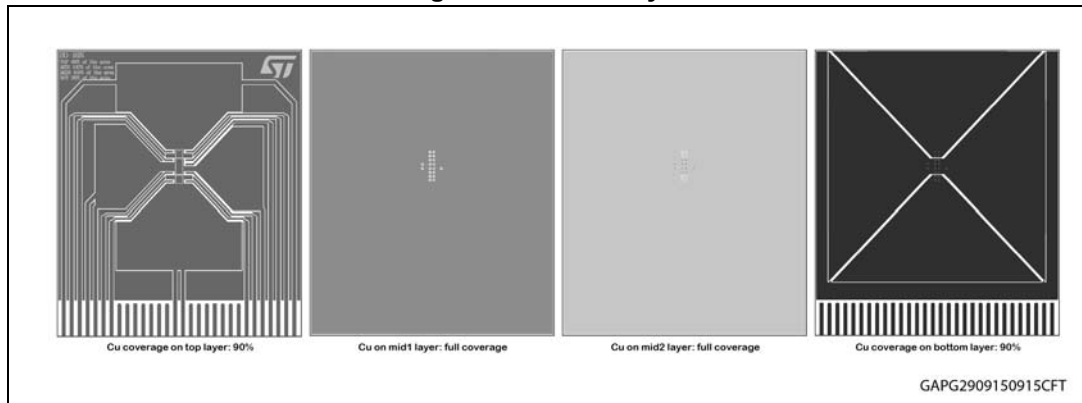


Figure 22. PCB 4 layer



Note: Board finish thickness 1.6 mm +/- 10%; Board double layer and four layers; Board dimension 77x86 mm; Board Material FR4; Cu thickness 0.070mm (outer layers); Cu thickness 0.035mm (inner layers); Thermal via separation 1.2 mm; Thermal via diameter 0.3 mm +/- 0.08 mm; Cu thickness on vias 0.025 mm.

## 4.2 Package thermal data

### 4.2.1 Thermal characterization in steady state conditions

Figure 23. Chipset configuration configuration in steady state conditions

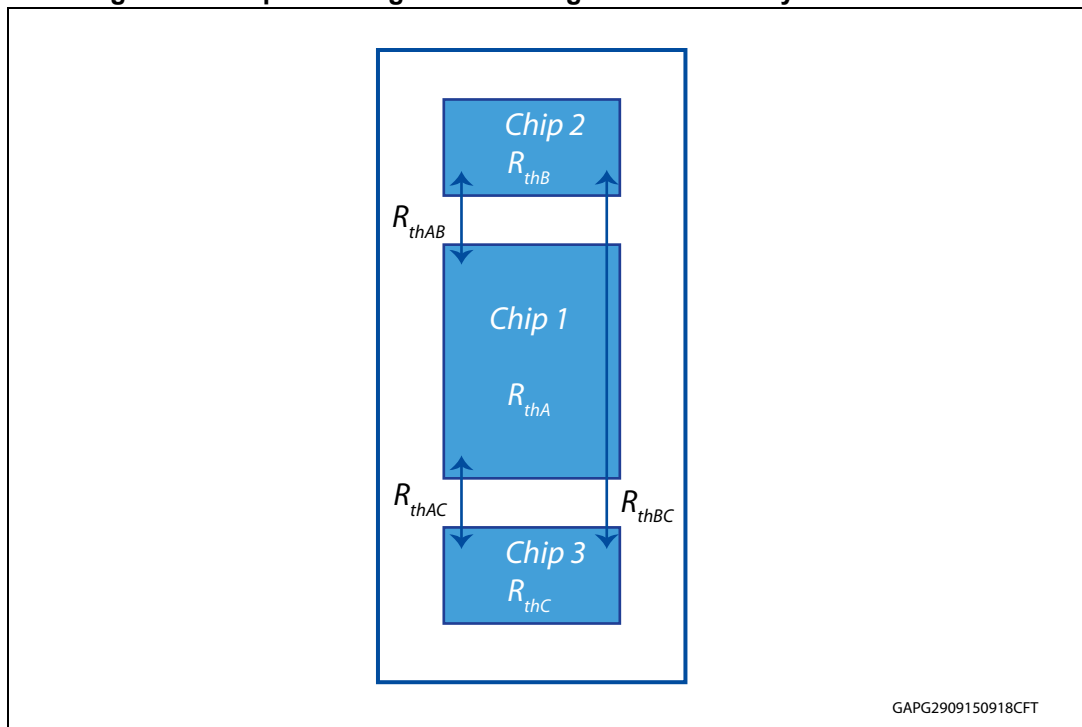


Figure 24. Auto and mutual  $R_{thj-amb}$  vs. PCB heat-sink area in open box free air condition

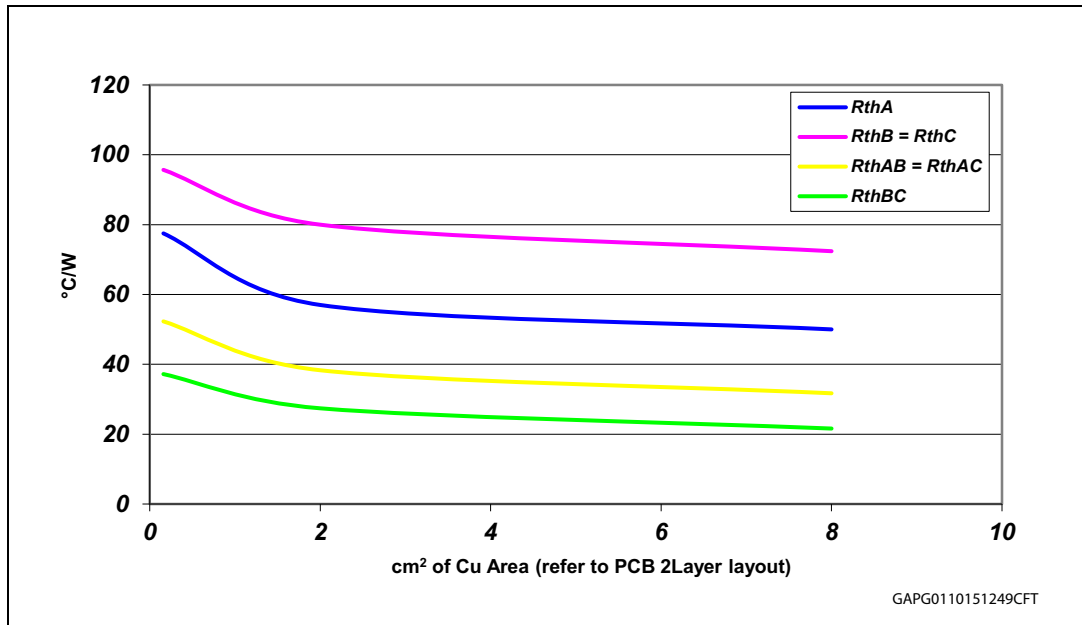


Table 15. Thermal model for junction temperature calculation in steady-state conditions\

Chip 1	Chip 2	Chip 3	Tjchip1	Tjchip2	Tjchip3
ON	OFF	ON	$P_{dchip1} \cdot R_{thA} + P_{dchip3} \cdot R_{thAC} + T_{amb}$	$P_{dchip1} \cdot R_{thAB} + P_{dchip3} \cdot R_{thBC} + T_{amb}$	$P_{dchip1} \cdot R_{thAC} + P_{dchip3} \cdot R_{thC} + T_{amb}$
ON	ON	OFF	$P_{dchip1} \cdot R_{thA} + P_{dchip2} \cdot R_{thAB} + T_{amb}$	$P_{dchip1} \cdot R_{thAB} + P_{dchip2} \cdot R_{thB} + T_{amb}$	$P_{dchip1} \cdot R_{thAC} + P_{dchip2} \cdot R_{thBC} + T_{amb}$
ON	OFF	OFF	$P_{dchip1} \cdot R_{thA} + T_{amb}$	$P_{dchip1} \cdot R_{thAB} + T_{amb}$	$P_{dchip1} \cdot R_{thAC} + T_{amb}$
ON	ON	ON	$P_{dchip1} \cdot R_{thA} + (P_{dchip2} + P_{dchip3}) \cdot R_{thAB} + T_{amb}$	$P_{dchip2} \cdot R_{thB} + P_{dchip1} \cdot R_{thAB} + P_{dchip3} \cdot R_{thBC} + T_{amb}$	$P_{dchip1} \cdot R_{thAB} + P_{dchip2} \cdot R_{thBC} + P_{dchip3} \cdot R_{thC} + T_{amb}$

### 4.2.2 Thermal characterization during transients

$$T_{hs} = P_{dhs} \cdot Z_{hs} + Z_{hsIs} \cdot (P_{dIsA} + P_{dIsB}) + T_{amb}$$

$$T_{IsA} = P_{dIsA} \cdot Z_{Is} + P_{dhs} \cdot Z_{hsIs} + P_{dIsB} \cdot Z_{IsIs} + T_{amb}$$

$$T_{IsB} = P_{dIsB} \cdot Z_{Is} + P_{dhs} \cdot Z_{hsIs} + P_{dIsA} \cdot Z_{IsIs} + T_{amb}$$

Figure 25. HSD thermal impedance junction ambient single pulse

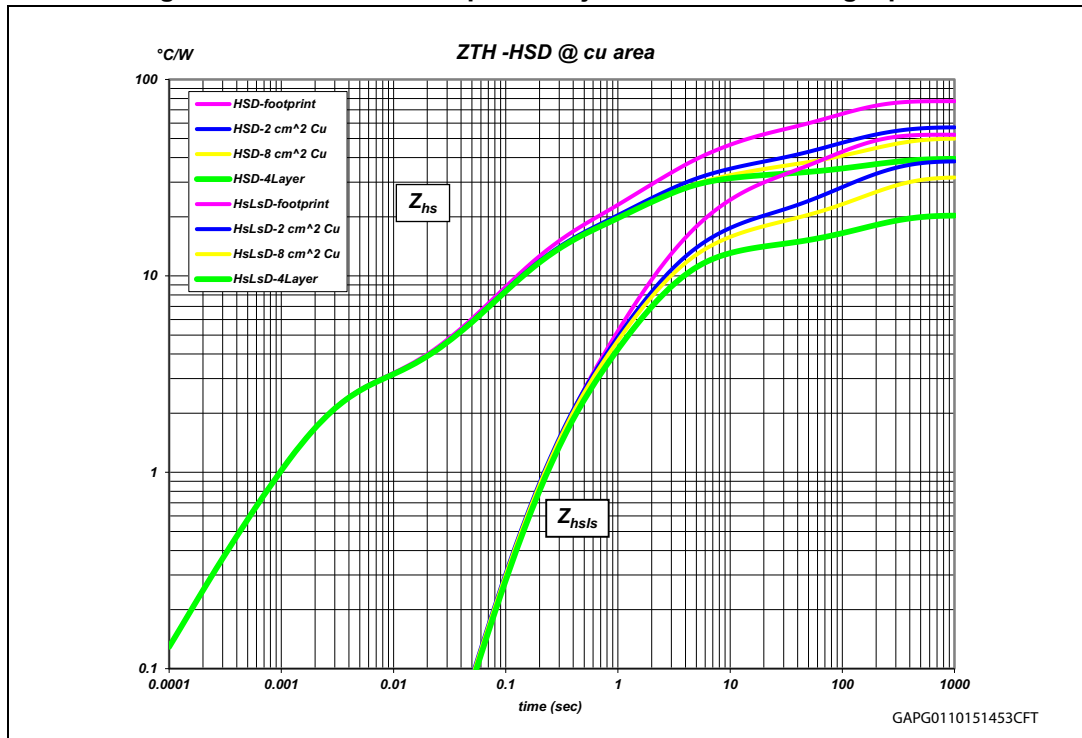


Figure 26. LSD thermal impedance junction ambient single pulse

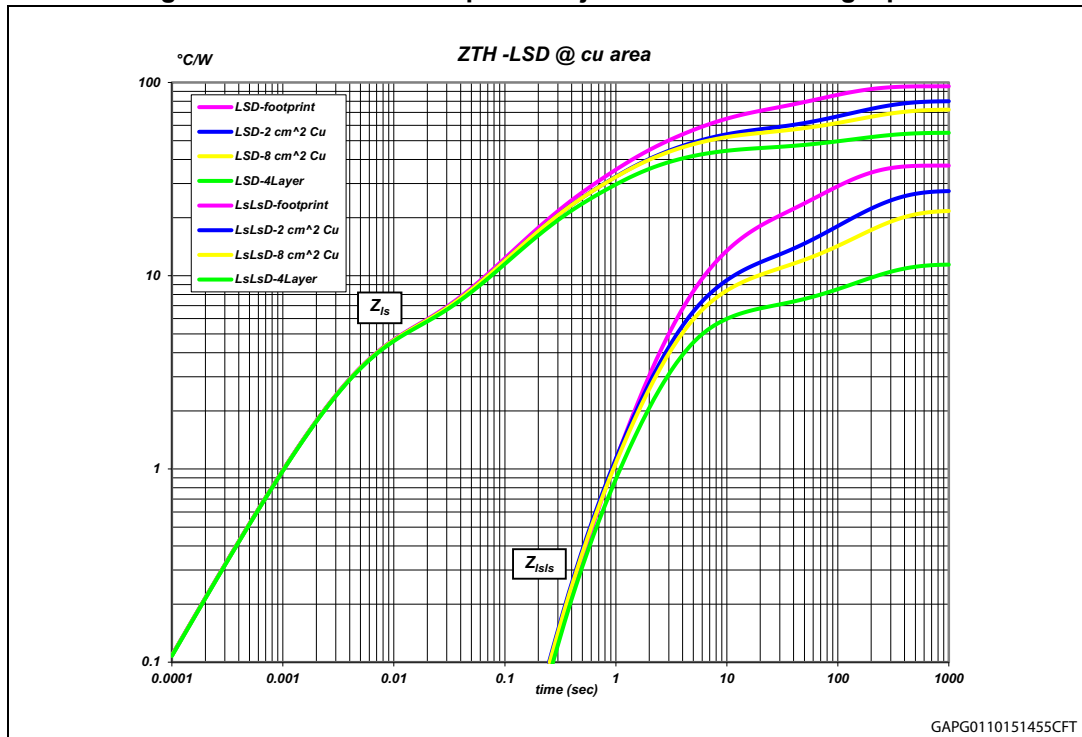


Figure 27. Electrical equivalent model

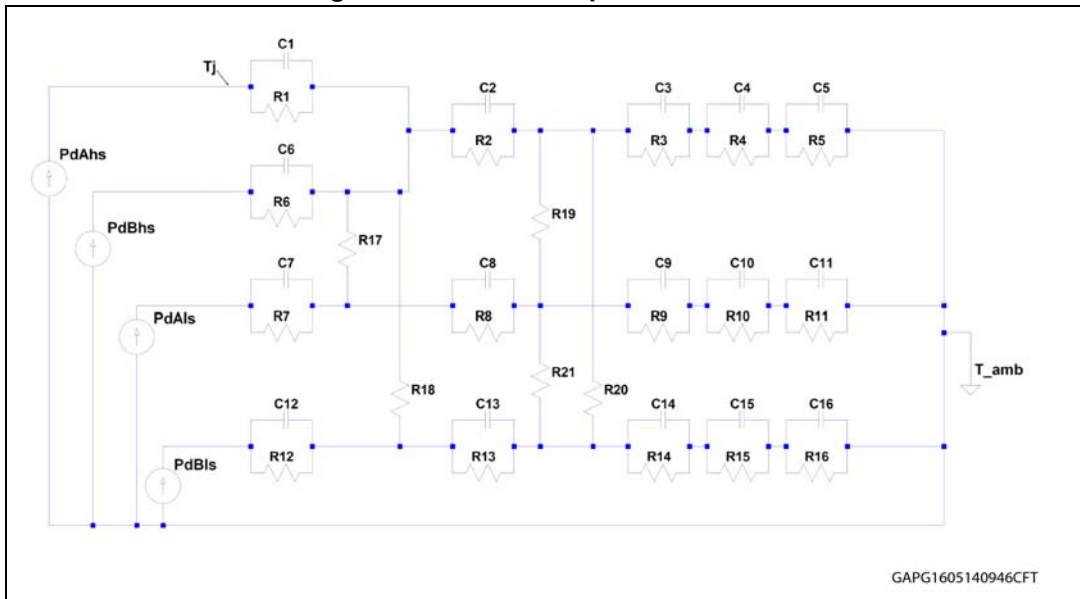


Table 16. Thermal parameters

Area/island (cm <sup>2</sup> )	FP	2	8	4L
R1 (°C/W)	2.4	2.4	2.4	2.4
R2 (°C/W)	12	12	12	12
R3 (°C/W)	31	26	26	30
R4 (°C/W)	42	12	12	8
R5 (°C/W)	86	46	31	16
R6 (°C/W)	2.4	2.4	2.4	2.4
R7 (°C/W)	4	4	4	4
R8 (°C/W)	11	11	11	11
R9 (°C/W)	32	32	32	32
R10 (°C/W)	68	52	48	22
R11 (°C/W)	75	80	60	26
R12 (°C/W)	4	4	4	4
R13 (°C/W)	11	11	11	11
R14 (°C/W)	32	32	32	32
R15 (°C/W)	68	52	48	10
R16 (°C/W)	75	80	60	26
R17 (°C/W)	120	100	100	100
R18 (°C/W)	120	100	100	100
R19 (°C/W)	180	170	170	170
R20 (°C/W)	180	170	170	170

Table 16. Thermal parameters (continued)

Area/island (cm <sup>2</sup> )	FP	2	8	4L
C1 (W·s/°C)	0.0008	0.0008	0.0008	0.0008
C2 (W·s/°C)	0.015	0.015	0.015	0.015
C3 (W·s/°C)	0.08	0.08	0.08	0.08
C4 (W·s/°C)	0.2	0.5	1	1
C5 (W·s/°C)	1.5	2	6	12
C6 (W·s/°C)	0.0008	0.0008	0.0008	0.0008
C7 (W·s/°C)	0.001	0.001	0.001	0.001
C8 (W·s/°C)	0.015	0.015	0.015	0.015
C9 (W·s/°C)	0.04	0.04	0.04	0.04
C10 (W·s/°C)	0.08	0.1	0.1	0.2
C11 (W·s/°C)	1	2.5	3	6
C12 (W·s/°C)	0.001	0.001	0.001	0.001
C13 (W·s/°C)	0.015	0.015	0.015	0.015
C14 (W·s/°C)	0.04	0.04	0.04	0.04
C15 (W·s/°C)	0.08	0.1	0.1	0.2
C16 (W·s/°C)	1	2.5	3	6



## 5 Package and packing information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).

ECOPACK® is an ST trademark.

### 5.1 SO-16N mechanical data

Figure 28. SO-16N package dimensions

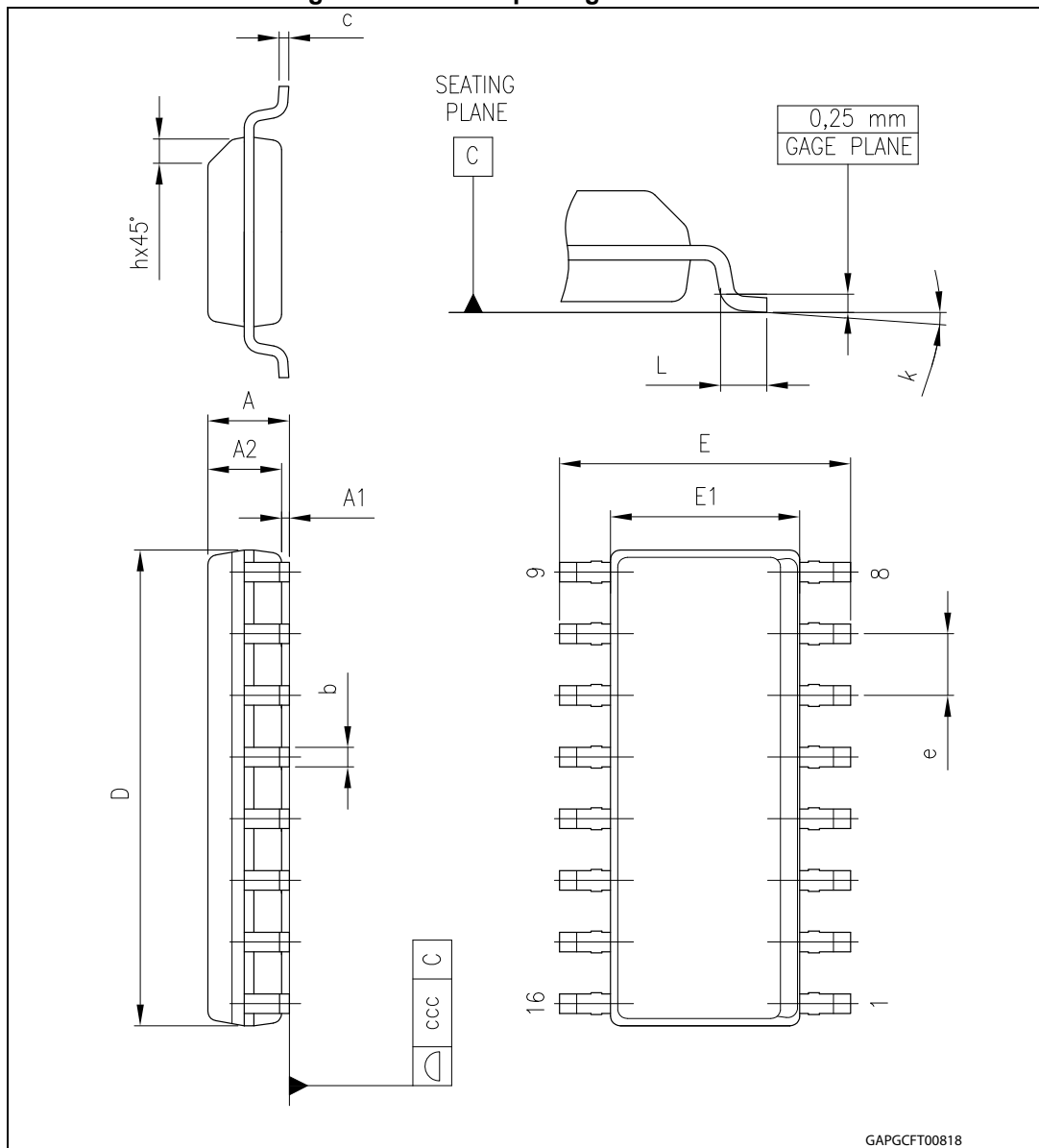


Table 17. SO-16N mechanical data

Symbol	Millimeters		
	Min.	Typ.	Max.
A			1.75
A1	0.10		0.25
A2	1.25		
b	0.31		0.51
c	0.17		0.25
D	9.80	9.90	10.00
E	5.80	6.00	6.20
E1	3.80	3.90	4.00
e		1.27	
h	0.25		0.50
L	0.40		1.27
k	0°		8°
ccc			0.1

## 5.2 SO-16N packing information

Figure 29. SO-16N reel 13"

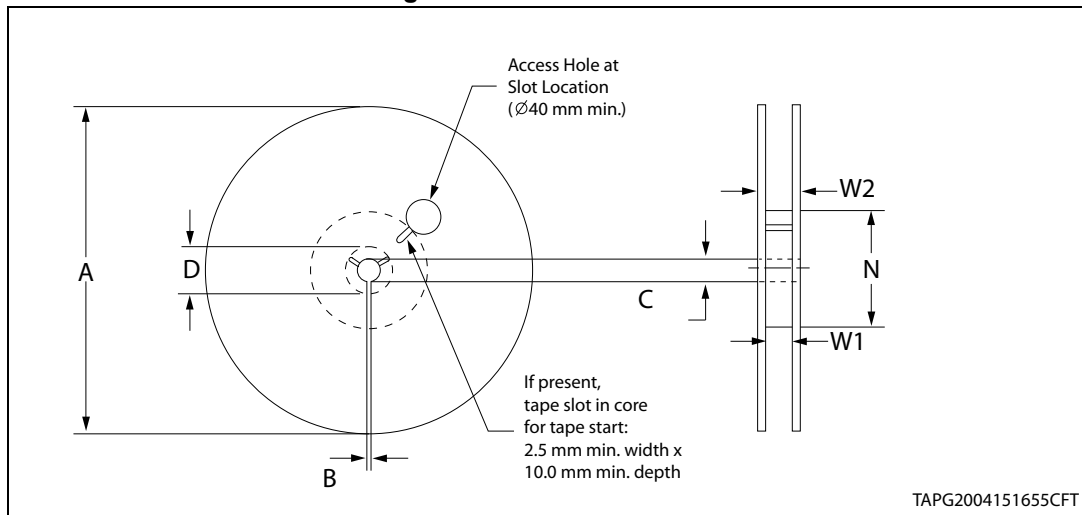


Table 18. Reel dimensions

Description	Value <sup>(1)</sup>
Base quantity	2500
Bulk quantity	2500
A (max)	330
B (min)	1.5
C (+0.5, -0.2)	13
D (min)	20.2
N	100
W1 (+2 /-0)	16.4
W2 (max)	22.4

1. All dimensions are in mm.

Figure 30. SO-16N rcarrier tape

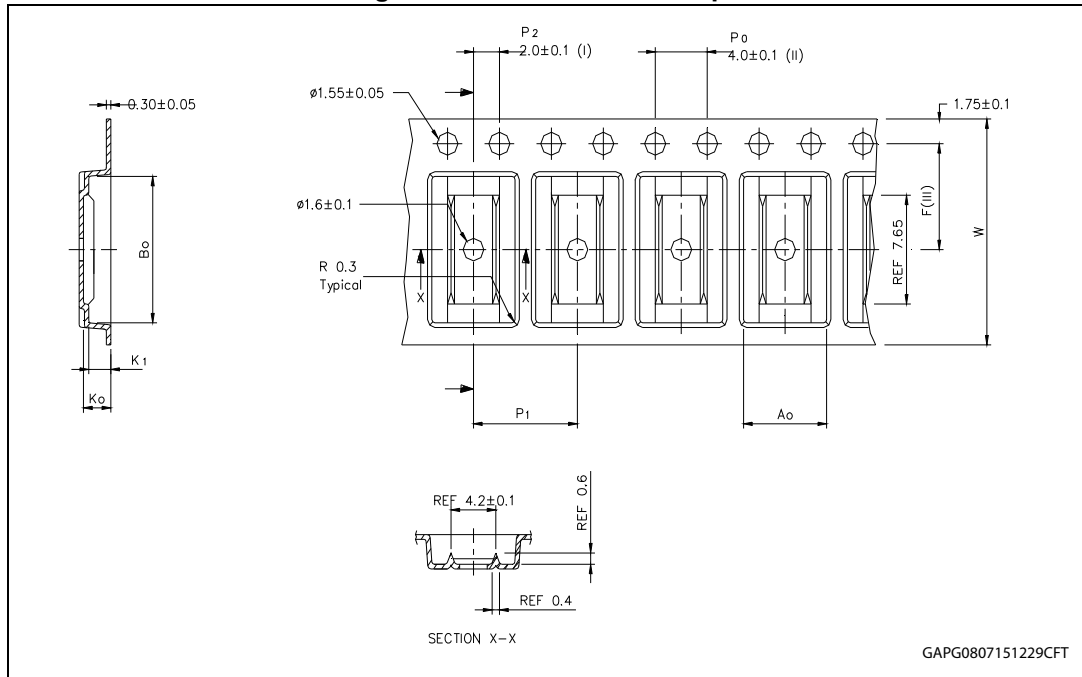


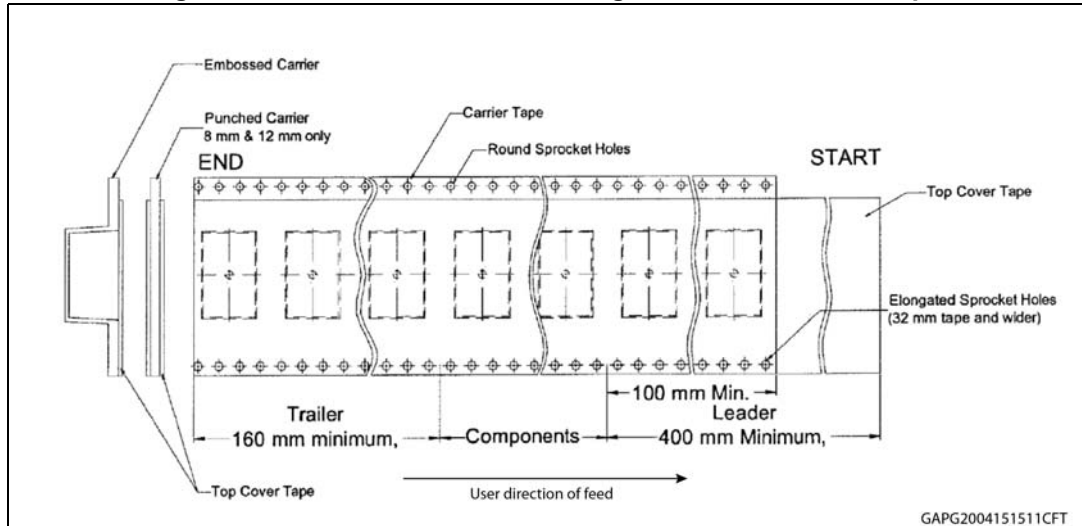
Table 19. SO-16N carrier tape dimensions

Description	Value
$A_0$	$6.55 \pm 0.1$
$B_0$	$10.38 \pm 0.1$
$K_0$	$2.10 \pm 0.1$
$K_1$	$1.80 \pm 0.1$
F	$7.50 \pm 0.1$

Table 19. SO-16N carrier tape dimensions (continued)

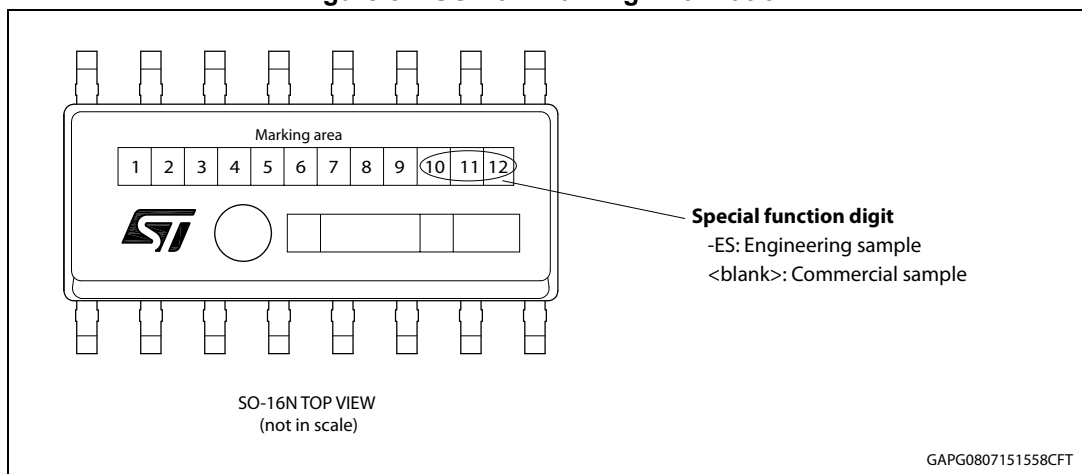
Description	Value
P <sub>1</sub>	8.00 ± 0.1
W	16.00 ± 0.3

Figure 31. SO-16N schematic drawing of leader and trailer tape



### 5.3 SO-16N marking information

Figure 32. SO-16N marking information



**Note:** *Engineering Samples: these samples can be clearly identified by a dedicated special symbol in the marking of each unit. These samples are intended to be used for electrical compatibility evaluation only; usage for any other purpose may be agreed only upon written authorization by ST. ST is not liable for any customer usage in production and/or in reliability qualification trials.*

*Commercial Samples: fully qualified parts from ST standard production with no usage restrictions.*

## 6 Revision history

**Table 20. Document revision history**

Date	Revision	Changes
16-Jul-2015	1	Initial release.
06-Oct-2015	2	<p><i>Table 4: Absolute maximum ratings:</i></p> <ul style="list-style-type: none"> <li>- I<sub>GND</sub>: removed row</li> </ul> <p>Updated <i>Table 5: Thermal data</i></p> <p><i>Table 6: Power section:</i></p> <ul style="list-style-type: none"> <li>- V<sub>f</sub>: updated parameter</li> </ul> <p><i>Table 8: Switching (V<sub>CC</sub> = 13 V, R<sub>LOAD</sub> = 3.7 Ω):</i></p> <ul style="list-style-type: none"> <li>- t<sub>cross</sub>: updated value</li> </ul> <p><i>Table 9: Protections and diagnostics (V<sub>CC</sub> = 7 V up to 18 V; -40 °C &lt; T<sub>j</sub> &lt; 150 °C):</i></p> <ul style="list-style-type: none"> <li>- t<sub>DSTKON</sub>: updated value</li> </ul> <p><i>Table 10: CS (7 V &lt; V<sub>CC</sub> &lt; 18 V):</i></p> <ul style="list-style-type: none"> <li>- K<sub>1</sub>, K<sub>2</sub>, K<sub>3</sub>, I<sub>SENSE_SAT</sub>, I<sub>OUT_SAT</sub>: updated values</li> </ul> <p>Updated <i>Figure 9: Input reset time for HSD - fault unlatch</i> and <i>Figure 10: Input reset time for LSD - fault unlatch</i></p> <p>Added <i>Section 2.4: Waveforms</i> and Updated <i>Chapter 3: Application information</i></p>
15-Oct-2015	3	<p><i>Table 9: Protections and diagnostics (V<sub>CC</sub> = 7 V up to 18 V; -40 °C &lt; T<sub>j</sub> &lt; 150 °C):</i></p> <ul style="list-style-type: none"> <li>- V<sub>CL</sub>: updated test conditions</li> </ul>
21-Oct-2015	4	Updated <i>Table 12: On-state fault conditions- truth table</i>
24-May-2016	5	<p><i>Table 8: Switching (V<sub>CC</sub> = 13 V, R<sub>LOAD</sub> = 3.7 Ω):</i></p> <ul style="list-style-type: none"> <li>- t<sub>r</sub>, t<sub>f</sub>: updated maximum values</li> </ul> <p><i>Table 9: Protections and diagnostics (V<sub>CC</sub> = 7 V up to 18 V; -40 °C &lt; T<sub>j</sub> &lt; 150 °C):</i></p> <ul style="list-style-type: none"> <li>- t<sub>DSTKON</sub>: updated maximum value</li> </ul> <p><i>Table 10: CS (7 V &lt; V<sub>CC</sub> &lt; 18 V):</i></p> <ul style="list-style-type: none"> <li>- I<sub>SENSE_SAT</sub>: added reference to table footnote 2</li> </ul> <p>Updated <i>Table 12: On-state fault conditions- truth table</i></p>

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